Radiation Report

UC1708-SP Total Ionizing Dose (TID) Lookahead Radiation Report

ABSTRACT

This report discusses the results of the Total Ionizing Dose (TID) testing for the Texas Instruments dual non-inverting power driver UC1708-SP. The study was done to determine TID effects under low dose rate (LDR) up to 40 krad(Si). The results show that all samples passed within the specified limits up to 40 krad(Si).

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Trademarks

1 Device Information

1.1 Product Description

The UC1708 family of power drivers are made with high-speed, high-voltage, Schottky process-to-interface control functions and high-power switching devices – particularly power MOSFETs. Operating over a 5-V to 35-V supply range, these devices contain two independent channels. The A and B inputs are compatible with TTL and CMOS logic families, but can withstand input voltages as high as VIN. Each output can source or sink up to 3 A as long as power dissipation limits are not exceeded.

1.2 Device Details

Table 1-1 lists the device information used in the initial TID characterization and qualification of LDR tests.

Table 1-1. Device and Exposure Details

TID LDR Details: 30 krad(Si) and 40 krad(Si)	
Package	8-pin JG
Technology	JI-PWR-1
Quantity Tested	20
LDR Radiation Facility	VPT Rad, Chelmsford, MA
LDR Dose Level	30 krad(Si), 40 krad(Si)
LDR Dose Rate	0.01 rad(Si)/s
LDR Radiation Source	Gamma cell Co60 (JLS-81-22)
Irradiation Temperature	Ambient, room temperature

Figure 1-1. UC1708-SP Device Used in Exposure

Table 1-2. Symbolization Table

Device Information	From UC1708 Image, Figure 1-1
Year, Quarter, Die Revision, and FAB code	9C-S
Date Code	1844A
Device	0051401VPA
GPN	UC1708
Bottom Marking	THA Q TI Logo

2 Total Dose Test Setup

2.1 Test Overview

The UC1708 was tested according to MIL-STD-883, Test Method 1019.9. For this testing, Condition D was used. For this test, one group was irradiated up to a radiation level of 30 krad(Si)/s, and the other group was irradiated up to a radiation level of 40 krad(Si)/s. Both groups were then put through electrical parametric testing on the Automated Test Equipment (ATE). Post irradiation testing showed that the devices were functional, passing all parametric tests.

2.2 Test Description and Facilities

The UC1708 LDR exposure was performed on biased and unbiased devices in a Co60 gamma cell under a 10-mrad(Si)/s exposure rate. The dose rate of the irradiator used in the exposure ranges from < 10 mrad(Si)/s to a maximum of approximately 84 rad(Si)/s, determined by the distance from the source. For the LDR exposure (10 mrad(Si)/s), the test box was positioned approximately 2 m from the source.

The exposure boards are housed in a lead-aluminum box (as specified in MIL-STD-883 TM 1019.9) to harden the gamma spectrum and minimize dose enhancement effects. The irradiator calibration is maintained by Logmire Laboratories using Thermoluminescence Dosimeters (TLDs) traceable to the National Institute of Standards and Technology (NIST) and the dosimetry was verified using TLDs prior to the radiation exposures. After exposure, the devices were packed in dry ice (per MIL-STD-883 Method 1019.9 section 3.10) and returned to TI Dallas for a post radiation electrical evaluation using Texas Instruments production Automated Test Equipment (ATE). ATE test limits are set per SMD electrical limits based on initial qualification and characterization data. Post-radiation measurements were taken within 30 minutes of removing the devices from the dry ice container. The devices were allowed to reach room temperature prior to electrical post-radiation measurements.

2.3 Test Setup Details

The devices under LDR exposure were irradiated in both biased and unbiased conditions. Both conditions are described as follows.

1. **Unbiased** - - *For the unbiased LDR conditions, the exposure was performed with all pins grounded.*
2. **Biased** - - *Figure 2-1 shows the diagram for LDR exposure with biased condition.*

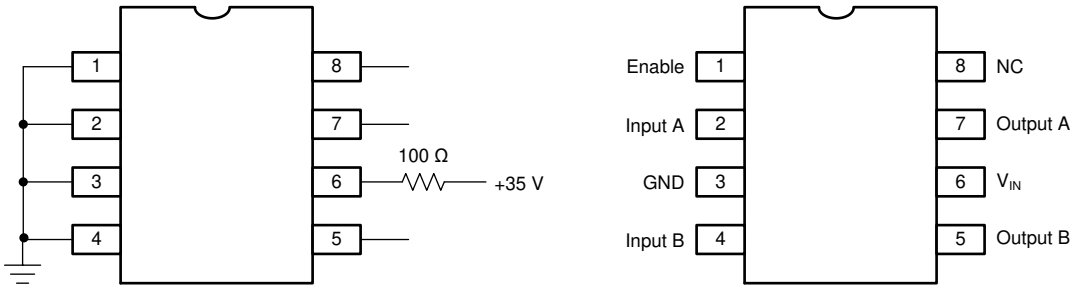


Figure 2-1. Bias Diagram Used in TID Exposure

2.4 Test Configuration and Condition

LDR devices were stressed at 30 krad(Si) and 40 krad(Si) for biased and unbiased conditions.

Table 2-1. LDR = 30- and 40-krad(Si)/s Biased Device Information

Total Samples: 10	
Exposure Level:	
30 krad(Si)	40 krad(Si)
3, 6, 8, 10, 15	16, 18, 7, 2, 12

Table 2-2. LDR = 30- and 40-krad(Si)/s Unbiased Device Information

Total Samples: 10	
Exposure Level:	
30 krad(Si)	40 krad(Si)
1, 11, 20, 14, 19	17, 5, 13, 4, 9

3 Total Ionizing Dose Characterization Test Results

The parametric data for the UC1708 passes up to 40-krad(Si) LDR TID.

The drift of SMD electrical parameters through LDR were within the pre-rad characterization limits.

See Appendix A for graphs and drifts.

3.1 Specification Compliance Matrix (Electrical Characteristics)

Unless otherwise stated, VIN = 10 V to 35 V, and these specifications apply for: –55°C < TA < 125°C for UC1708. TA = TJ.

PARAMETER	TEST CONDITIONS	UC1708-SP Datasheet				Test(s)
		MIN	TYP	MAX	UNIT	
V_{in} Supply Current	Outputs Low		18	26	mA	IVIN,SUPPLY CURRENT,VIN10V,OUTPUTS LOW IVIN,SUPPLY CURRENT,VIN35V,OUTPUTS LOW
	Outputs high		14	18		IVIN,SUPPLY CURRENT,VIN35V,OUTPUTS HIGH IVIN,SUPPLY CURRENT,VIN10V,OUTPUTS HIGH
	Enable = 0 V		1	4		VIN LEAKAGE I,VIN10V,ENABLE0V VIN LEAKAGE I,VIN35V,ENABLE0V
A, B Input current low	$V_{A,B}$= 0.4V	-1	-0.6		mA	IIL OF INPUT A,VIL0.4V,VIN35V IIL OF INPUT A,VIL0.4V,VIN10V IIL OF INPUT B,VIL0.4V,VIN10V IIL OF INPUT B,VIL0.4V,VIN35V
A, B Input current high	$V_{A,B}$= 2.4V	-200		50	µA	IIH OF INPUT A,VIH2.4V,VIN10V IIH OF INPUT A,VIH2.4V,VIN35V IIH OF INPUT B,VIH2.4V,VIN10V IIH OF INPUT B,VIH2.4V,VIN35V
A, B Input leakage current high	$V_{A,B}$= 35.3V			200	µA	INPUT A LEAKAGE,VIH35.3V,VIN35V INPUT A LEAKAGE,VIH10.3V,VIN10V INPUT B LEAKAGE,VIH35.3V,VIN35V INPUT B LEAKAGE,VIH10.3V,VIN10V
Enable input current low	V_{ENABLE} = 0V	-600	-460	200	µA	IIL OF ENABLE,VIL0V,VIN10V IIL OF ENABLE,VIL0V,VIN35V
Enable input current high	V_{ENABLE} = 6.2V		2.8	200	µA	IIH OF ENABLE,VIH6.2V,VIN35V IIH OF ENABLE,VIH6.2V,VIN10V
Enable threshold rising			2.4	3.6	V	THOLD OF ENABLE,OUTPUT L TO H,VIN10V THOLD OF ENABLE,OUTPUT L TO H,VIN35V
Enable threshold falling		1.0		3.4	V	THOLD OF ENABLE,OUTPUT H TO L,VIN10V THOLD OF ENABLE,OUTPUT H TO L,VIN35V

3.1 Specification Compliance Matrix (Electrical Characteristics) (continued)

Unless otherwise stated, VIN = 10 V to 35 V, and these specifications apply for: –55°C < TA < 125°C for UC1708. TA = TJ.

PARAMETER	TEST CONDITIONS	UC1708-SP Datasheet				Test(s)
		MIN	TYP	MAX	UNIT	
$V_{in} – V_{out}$ Output High Saturation	I_{OUT} = –50mA			2.0	V	VOH SAT OUTPUT A,IOH-50MA,VIN35V VOH SAT OUTPUT A,IOH-50MA,VIN10V VOH SAT A, 50MA, VIN5V VOH SAT OUTPUT B,IOH-50MA,VIN10V VOH SAT OUTPUT B,IOH-50MA,VIN35V VOH SAT B, 50MA, VIN5V
	I_{OUT} = –500mA			2.5	V	VOH SAT OUTPUT A,IOH-500MA,VIN35V VOH SAT OUTPUT A,IOH-500MA,VIN10V VOH SAT OUTPUT B,IOH-500MA,VIN10V VOH SAT OUTPUT B,IOH-500MA,VIN35V
V_{out} Output Low Saturation	I_{OUT} = 50mA			0.5	V	VOL OUTPUT A,IOL50MA,VIN10V VOL OUTPUT A,IOL50MA,VIN35V VOL OUTPUT A, 50MA, VIN5V VOL OUTPUT B,IOL50MA,VIN35V VOL OUTPUT B,IOL50MA,VIN10V VOL OUTPUT B, 50MA, VIN5V
	I_{OUT} = 500mA			2.5	V	VOL OUTPUT A,IOL500MA,VIN10V VOL OUTPUT A,IOL500MA,VIN35V VOL OUTPUT B,IOL500MA,VIN35V VOL OUTPUT B,IOL500MA,VIN10V

3.2 Specification Compliance Matrix (Switching Characteristics)

VIN = 20 V, delays measured to 10% output change.

PARAMETER	TEST CONDITIONS	UC1708-SP Datasheet				Test(s)
		MIN	TYP	MAX	UNIT	
FROM A,B INPUT TO OUTPUT:						
Rise Time Delay (TPLH)	CL = 0pF		25	40	ns	RISE TIME DELAY,TPLH_A,CL0 RISE TIME DELAY,TPLH_B,CL0
	CL = 2200pF		25	50	ns	RISE TIME DELAY,TPLH_A,CL2.2NF RISE TIME DELAY,TPLH_B,CL2.2NF
10% to 90% Rise (TTLH)	CL = 0pF		55	75	ns	RISE TIME OUTPUT A,TRISE_A,CL0 RISE TIME OUTPUT B,TRISE_B,CL0
	CL = 2200pF		40	85	ns	RISE TIME OUTPUT A,TRISE_A,CL2.2NF RISE TIME OUTPUT B,TRISE_B,CL2.2NF
Fall Time Delay (TPLH)	CL = 0pF		25	40	ns	FALL TIME DELAY,TPHL_A,CL0 FALL TIME DELAY,TPHL_B,CL0
	CL = 2200pF		35	50	ns	FALL TIME DELAY,TPHL_A,CL2.2NF FALL TIME DELAY,TPHL_B,CL2.2NF
90% to 10% Fall (TTHL)	CL = 0pF		15	20	ns	FALL TIME OUTPUT A,TFALL_A,CL0 FALL TIME OUTPUT B,TFALL_B,CL0
	CL = 2200pF		40	55	ns	FALL TIME OUTPUT A,TFALL_A,CL2.2NF FALL TIME OUTPUT B,TFALL_B,CL2.2NF
FROM SHUTDOWN INPUT TO OUTPUT:						
Total Supply Current	F = 200kHz, 50% duty cycle, both channels; CL = 0pF		23	25	mA	ICC1,DYNAMIC ICC,VIN20V,CL0
	F = 200kHz, 50% duty cycle, both channels; CL = 2200pF		38	45		ICC2,DYNAMIC ICC,VIN20V,CL2.2NF

4 Applicable and Reference Documents

4.1 Applicable Documents

- *UC1708 Radiation-Hardness-Assured Dual Non-Inverting Power Driver* data sheet

4.2 Reference Documents

Texas Instruments total ionizing dose radiation (total dose) test procedure follows the standards put forth in MIL-STD-883 TM 1019. The document can be found at the DLA website.

A TID Data

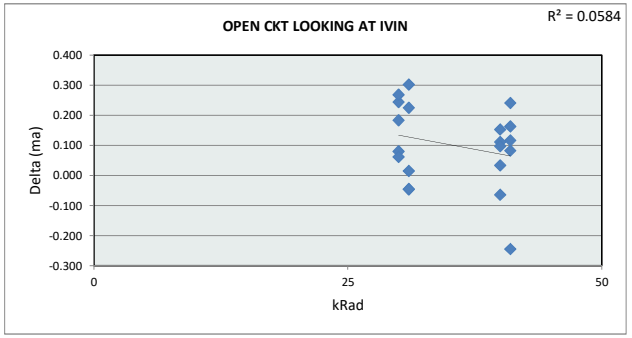
Table A-1. Bias vs Unbias Mapping

Note: All devices were tested at either 30 krad(Si)/s or 40 krad(Si)/s. The biased devices are labeled "31" and "41" in the data in order to create separation between biased and unbiased devices. The purpose of this table is to map the biased and unbiased devices.

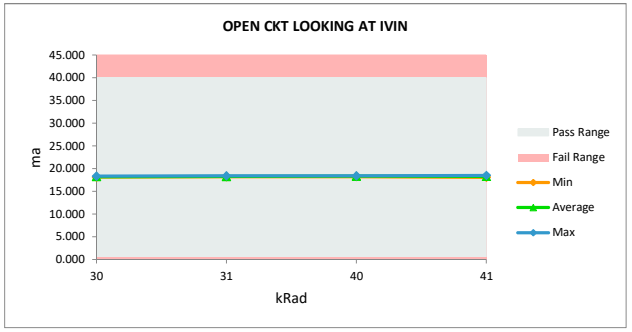
krad(Si)	Description	Unit #
30	30-krad(Si) UNBIASED	1, 11, 20, 14, 19
31	30-krad(Si) BIASED	3, 6, 8, 10, 15
40	40-krad(Si) UNBIASED	17, 5, 13, 4, 9
41	40-krad(Si) BIASED	16, 18, 7, 2, 12

UC1708-SP TID Report

	OPEN CKT LOOKING AT IVIN		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	40	40	
Min Limit	0.5	0.5	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	18.396	18.315	0.080
30	11	18.313	18.129	0.184
30	20	18.415	18.171	0.244
30	14	18.389	18.327	0.062
30	19	18.530	18.262	0.268
40	17	18.400	18.367	0.034
40	5	18.348	18.236	0.111
40	13	18.431	18.333	0.097
40	4	18.241	18.305	-0.064
40	9	18.567	18.414	0.153
31	3	18.383	18.430	-0.046
31	6	18.415	18.190	0.225
31	8	18.497	18.195	0.302
31	10	18.220	18.205	0.015
31	15	18.203	18.248	-0.045
41	16	18.295	18.212	0.083
41	18	18.490	18.374	0.117
41	7	18.261	18.505	-0.245
41	2	18.484	18.322	0.163
41	12	18.299	18.058	0.241
	Max	18.567	18.505	0.302
	Average	18.379	18.280	0.099
	Min	18.203	18.058	-0.245
	Std Dev	0.105	0.110	0.134

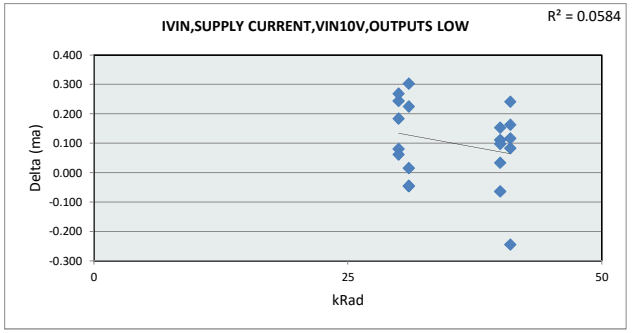


	OPEN CKT LOOKING AT IVIN			
Test Site				
Tester				
Test Number				
Max Limit	40	ma		
Min Limit	0.5	ma		
kRad	30	31	40	41
LL	0.500	0.500	0.500	0.500
Min	18.129	18.190	18.237	18.058
Average	18.241	18.253	18.331	18.294
Max	18.327	18.430	18.414	18.505
UL	40.000	40.000	40.000	40.000

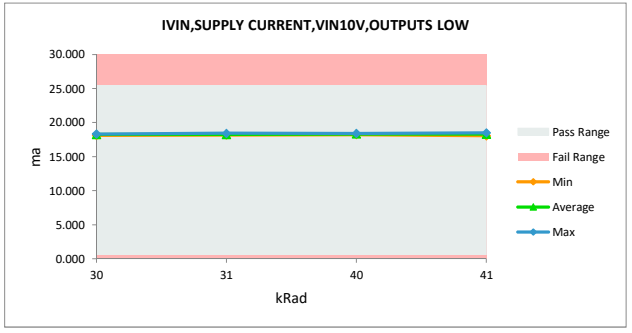


UC1708-SP TID Report

	IVIN,SUPPLY CURRENT,VIN10V,OUTPUTS LOW		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	25.4	25.4	
Min Limit	0.5	0.5	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	18.396	18.315	0.080
30	11	18.313	18.129	0.184
30	20	18.415	18.171	0.244
30	14	18.389	18.327	0.062
30	19	18.530	18.262	0.268
40	17	18.400	18.367	0.034
40	5	18.348	18.236	0.111
40	13	18.431	18.333	0.097
40	4	18.241	18.305	-0.064
40	9	18.567	18.414	0.153
31	3	18.383	18.430	-0.046
31	6	18.415	18.190	0.225
31	8	18.497	18.195	0.302
31	10	18.220	18.205	0.015
31	15	18.203	18.248	-0.045
41	16	18.295	18.212	0.083
41	18	18.490	18.374	0.117
41	7	18.261	18.505	-0.245
41	2	18.484	18.322	0.163
41	12	18.299	18.058	0.241
	Max	18.567	18.505	0.302
	Average	18.379	18.280	0.099
	Min	18.203	18.058	-0.245
	Std Dev	0.105	0.110	0.134

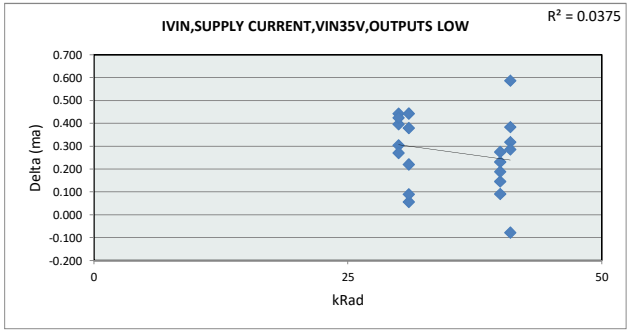


	IVIN,SUPPLY CURRENT,VIN10V,OU			
Test Site				
Tester				
Test Number				
Max Limit	25.4	ma		
Min Limit	0.5	ma		
kRad	30	31	40	41
LL	0.500	0.500	0.500	0.500
Min	18.129	18.190	18.237	18.058
Average	18.241	18.253	18.331	18.294
Max	18.327	18.430	18.414	18.505
UL	25.400	25.400	25.400	25.400

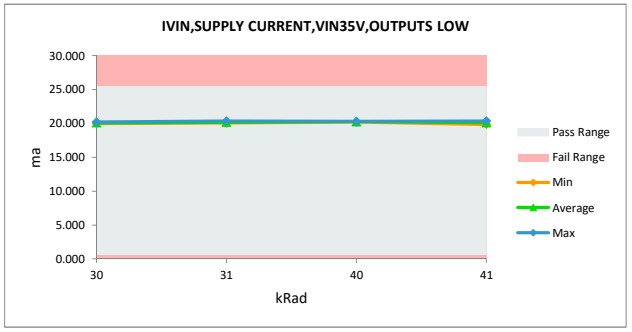


UC1708-SP TID Report

	IVIN,SUPPLY CURRENT,VIN35V,OUTPUTS LOW		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	25.4	25.4	
Min Limit	0.5	0.5	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	20.513	20.209	0.304
30	11	20.426	19.984	0.442
30	20	20.414	20.018	0.396
30	14	20.386	20.116	0.270
30	19	20.494	20.070	0.424
40	17	20.393	20.247	0.146
40	5	20.431	20.199	0.231
40	13	20.536	20.261	0.275
40	4	20.278	20.187	0.091
40	9	20.490	20.301	0.189
31	3	20.395	20.338	0.057
31	6	20.515	20.136	0.379
31	8	20.507	20.064	0.443
31	10	20.315	20.094	0.220
31	15	20.232	20.142	0.090
41	16	20.342	20.024	0.317
41	18	20.555	20.269	0.286
41	7	20.280	20.358	-0.078
41	2	20.507	20.124	0.383
41	12	20.433	19.847	0.586
	Max	20.555	20.358	0.586
	Average	20.422	20.150	0.273
	Min	20.232	19.847	-0.078
	Std Dev	0.095	0.129	0.160

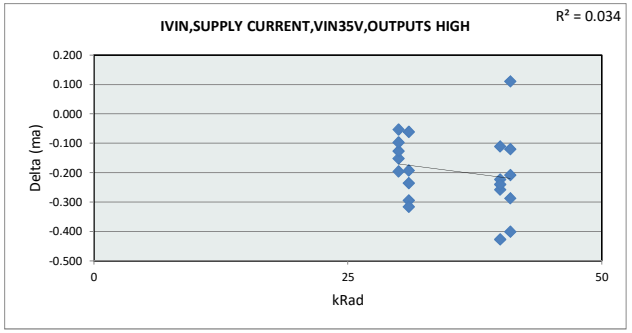


	IVIN,SUPPLY CURRENT,VIN35V,OU			
Test Site				
Tester				
Test Number				
Max Limit	25.4	ma		
Min Limit	0.5	ma		
kRad	30	31	40	41
LL	0.500	0.500	0.500	0.500
Min	19.984	20.064	20.187	19.847
Average	20.079	20.155	20.239	20.124
Max	20.209	20.338	20.301	20.358
UL	25.400	25.400	25.400	25.400

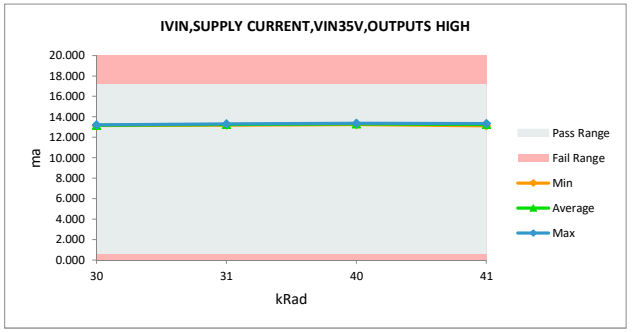


UC1708-SP TID Report

	IVIN,SUPPLY CURRENT,VIN35V,OUTPUTS HIGH		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	17.1	17.1	
Min Limit	0.5	0.5	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	13.061	13.213	-0.152
30	11	13.011	13.138	-0.127
30	20	13.088	13.142	-0.054
30	14	13.020	13.216	-0.196
30	19	13.092	13.189	-0.097
40	17	13.005	13.263	-0.258
40	5	13.064	13.288	-0.223
40	13	13.131	13.242	-0.111
40	4	12.945	13.372	-0.427
40	9	13.103	13.344	-0.240
31	3	13.020	13.315	-0.294
31	6	13.132	13.193	-0.062
31	8	13.115	13.307	-0.193
31	10	12.977	13.213	-0.236
31	15	12.930	13.245	-0.316
41	16	12.985	13.193	-0.208
41	18	13.047	13.334	-0.287
41	7	12.942	13.343	-0.401
41	2	13.350	13.240	0.110
41	12	13.005	13.125	-0.120
	Max	13.350	13.372	0.110
	Average	13.051	13.246	-0.195
	Min	12.930	13.125	-0.427
	Std Dev	0.094	0.073	0.125

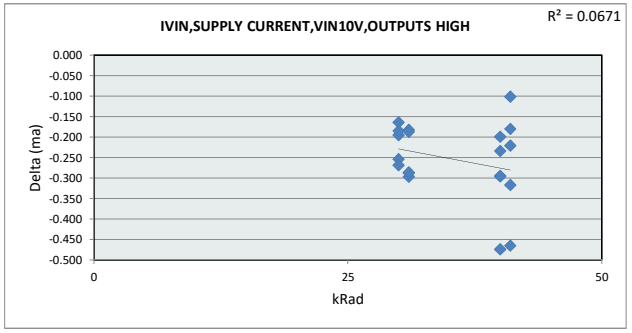


	IVIN,SUPPLY CURRENT,VIN35V,OU			
Test Site				
Tester				
Test Number				
Max Limit	17.1	ma		
Min Limit	0.5	ma		
kRad	30	31	40	41
LL	0.500	0.500	0.500	0.500
Min	13.138	13.193	13.242	13.125
Average	13.180	13.255	13.302	13.247
Max	13.216	13.315	13.372	13.343
UL	17.100	17.100	17.100	17.100

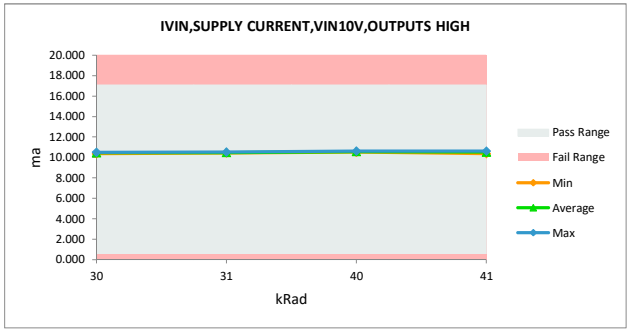


UC1708-SP TID Report

	IVIN,SUPPLY CURRENT,VIN10V,OUTPUTS HIGH		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	17.1	17.1	
Min Limit	0.5	0.5	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	10.225	10.479	-0.254
30	11	10.202	10.366	-0.164
30	20	10.313	10.507	-0.195
30	14	10.187	10.455	-0.268
30	19	10.310	10.494	-0.185
40	17	10.317	10.550	-0.234
40	5	10.250	10.546	-0.296
40	13	10.313	10.512	-0.199
40	4	10.096	10.570	-0.474
40	9	10.328	10.623	-0.295
31	3	10.230	10.527	-0.297
31	6	10.278	10.460	-0.182
31	8	10.305	10.492	-0.187
31	10	10.153	10.441	-0.288
31	15	10.148	10.435	-0.286
41	16	10.187	10.367	-0.180
41	18	10.296	10.613	-0.317
41	7	10.152	10.617	-0.465
41	2	10.444	10.546	-0.101
41	12	10.197	10.418	-0.221
	Max	10.444	10.623	-0.101
	Average	10.246	10.501	-0.254
	Min	10.096	10.366	-0.474
	Std Dev	0.084	0.076	0.093

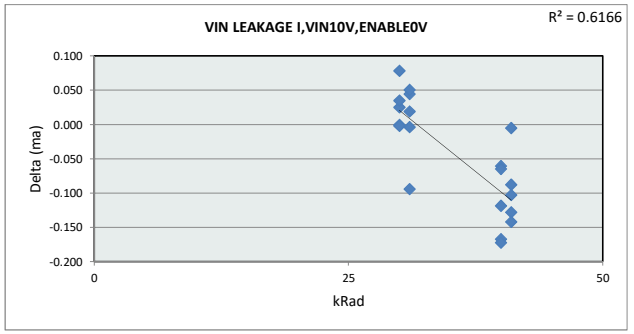


	IVIN,SUPPLY CURRENT,VIN10V,OU			
Test Site				
Tester				
Test Number				
Max Limit	17.1	ma		
Min Limit	0.5	ma		
kRad	30	31	40	41
LL	0.500	0.500	0.500	0.500
Min	10.366	10.435	10.512	10.367
Average	10.460	10.471	10.560	10.512
Max	10.508	10.527	10.623	10.617
UL	17.100	17.100	17.100	17.100

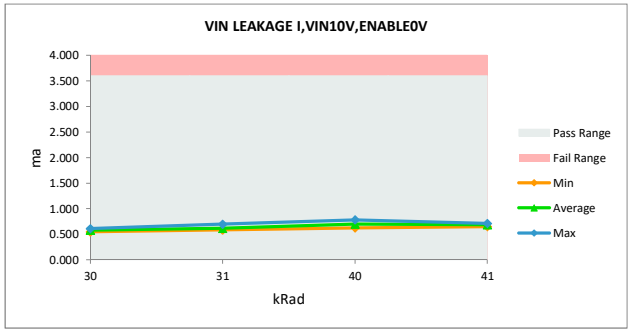


UC1708-SP TID Report

	VIN LEAKAGE I,VIN10V,ENABLE0V		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	3.6	3.6	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.629	0.604	0.025
30	11	0.644	0.609	0.035
30	20	0.625	0.547	0.078
30	14	0.577	0.577	-0.001
30	19	0.569	0.571	-0.002
40	17	0.533	0.700	-0.167
40	5	0.598	0.716	-0.118
40	13	0.610	0.782	-0.172
40	4	0.615	0.676	-0.061
40	9	0.562	0.627	-0.065
31	3	0.616	0.597	0.019
31	6	0.649	0.604	0.045
31	8	0.586	0.590	-0.004
31	10	0.636	0.586	0.051
31	15	0.604	0.698	-0.094
41	16	0.584	0.712	-0.128
41	18	0.539	0.681	-0.142
41	7	0.582	0.684	-0.103
41	2	0.642	0.647	-0.005
41	12	0.617	0.705	-0.088
	Max	0.649	0.782	0.078
	Average	0.601	0.646	-0.045
	Min	0.533	0.547	-0.172
	Std Dev	0.034	0.063	0.078



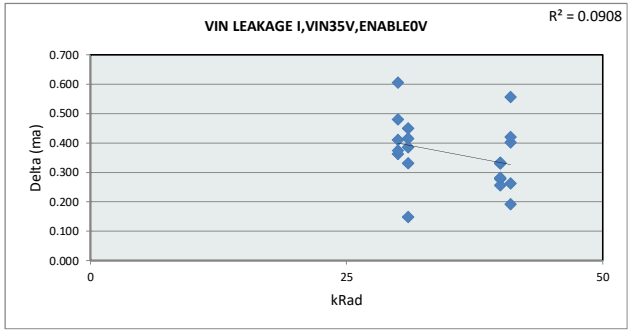
	VIN LEAKAGE I,VIN10V,ENABLE0V			
Test Site				
Tester				
Test Number				
Max Limit	3.6	ma		
Min Limit	0	ma		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.547	0.586	0.627	0.647
Average	0.582	0.615	0.700	0.686
Max	0.609	0.699	0.782	0.712
UL	3.600	3.600	3.600	3.600



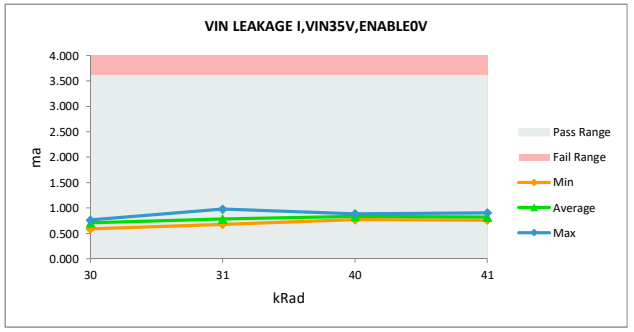
UC1708-SP TID Report

	VIN LEAKAGE I,VIN35V,ENABLE0V	
Test Site		
Tester		
Test Number		
Unit	ma	ma
Max Limit	3.6	3.6
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.342	0.737	0.605
30	11	1.205	0.725	0.480
30	20	1.130	0.720	0.411
30	14	1.126	0.763	0.363
30	19	0.964	0.590	0.374
40	17	1.102	0.772	0.330
40	5	1.107	0.830	0.277
40	13	1.143	0.887	0.256
40	4	1.181	0.849	0.333
40	9	1.116	0.835	0.281
31	3	1.135	0.720	0.415
31	6	1.130	0.799	0.331
31	8	1.066	0.681	0.385
31	10	1.203	0.753	0.450
31	15	1.126	0.978	0.148
41	16	1.111	0.849	0.262
41	18	1.097	0.905	0.192
41	7	1.169	0.767	0.402
41	2	1.183	0.762	0.421
41	12	1.374	0.818	0.556
	Max	1.374	0.978	0.605
	Average	1.151	0.787	0.364
	Min	0.964	0.590	0.148
	Std Dev	0.089	0.086	0.113

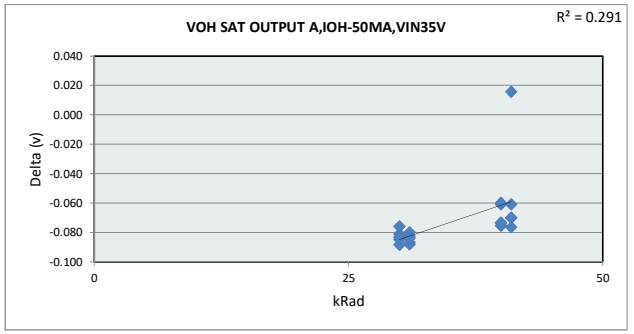


	VIN LEAKAGE I,VIN35V,ENABLE0V			
Test Site				
Tester				
Test Number				
Max Limit	3.6	ma		
Min Limit	0	ma		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.590	0.681	0.772	0.762
Average	0.707	0.786	0.835	0.820
Max	0.764	0.978	0.887	0.905
UL	3.600	3.600	3.600	3.600

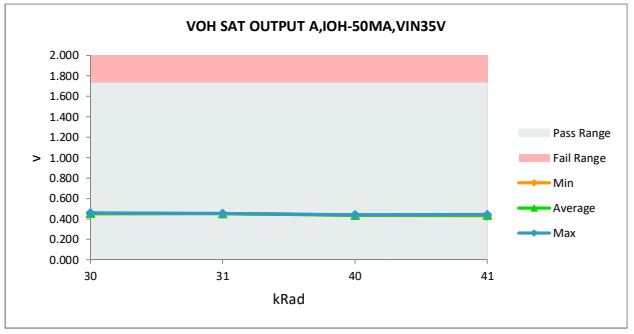


UC1708-SP TID Report

	VOH SAT OUTPUT A,IOH-50MA,VIN35V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	1.73	1.73	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.382	0.458	-0.076
30	11	0.372	0.461	-0.088
30	20	0.368	0.453	-0.085
30	14	0.370	0.451	-0.081
30	19	0.368	0.451	-0.083
40	17	0.373	0.434	-0.061
40	5	0.367	0.442	-0.075
40	13	0.364	0.438	-0.074
40	4	0.374	0.434	-0.060
40	9	0.369	0.442	-0.073
31	3	0.374	0.454	-0.080
31	6	0.367	0.454	-0.087
31	8	0.367	0.455	-0.088
31	10	0.370	0.453	-0.083
31	15	0.369	0.453	-0.084
41	16	0.373	0.434	-0.061
41	18	0.370	0.440	-0.070
41	7	0.370	0.440	-0.070
41	2	0.446	0.430	0.016
41	12	0.368	0.444	-0.076
	Max	0.446	0.461	0.016
	Average	0.374	0.446	-0.072
	Min	0.364	0.430	-0.088
	Std Dev	0.017	0.009	0.022

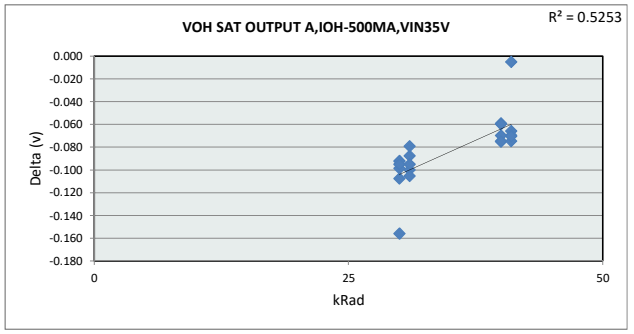


	VOH SAT OUTPUT A,IOH-50MA,VIN			
Test Site				
Tester				
Test Number				
Max Limit	1.73	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.451	0.453	0.434	0.430
Average	0.455	0.453	0.438	0.438
Max	0.461	0.455	0.442	0.445
UL	1.730	1.730	1.730	1.730

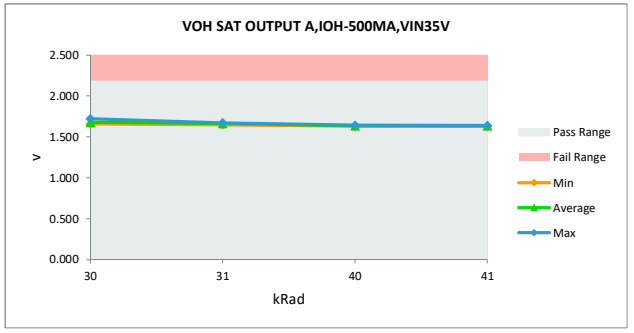


UC1708-SP TID Report

	VOH SAT OUTPUT A,IOH-500MA,VIN35V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	2.18	2.18	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.578	1.677	-0.099
30	11	1.566	1.722	-0.156
30	20	1.567	1.660	-0.092
30	14	1.569	1.677	-0.107
30	19	1.569	1.663	-0.095
40	17	1.572	1.631	-0.059
40	5	1.564	1.638	-0.075
40	13	1.564	1.634	-0.070
40	4	1.573	1.633	-0.060
40	9	1.569	1.643	-0.075
31	3	1.577	1.665	-0.088
31	6	1.569	1.648	-0.079
31	8	1.569	1.668	-0.100
31	10	1.572	1.667	-0.095
31	15	1.568	1.673	-0.105
41	16	1.567	1.633	-0.066
41	18	1.564	1.638	-0.075
41	7	1.569	1.638	-0.069
41	2	1.625	1.630	-0.005
41	12	1.571	1.641	-0.070
	Max	1.625	1.722	-0.005
	Average	1.572	1.654	-0.082
	Min	1.564	1.630	-0.156
	Std Dev	0.013	0.023	0.029



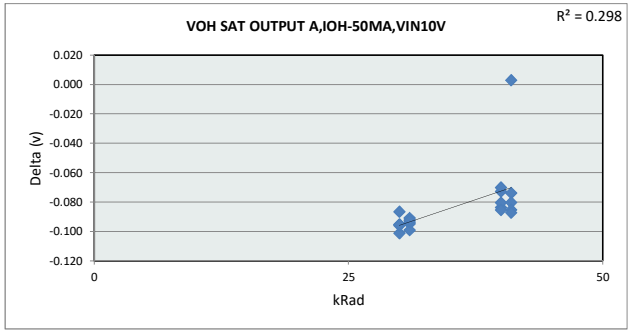
	VOH SAT OUTPUT A,IOH-500MA,V			
Test Site				
Tester				
Test Number				
Max Limit	2.18	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.660	1.648	1.631	1.630
Average	1.680	1.664	1.636	1.636
Max	1.722	1.673	1.644	1.641
UL	2.180	2.180	2.180	2.180



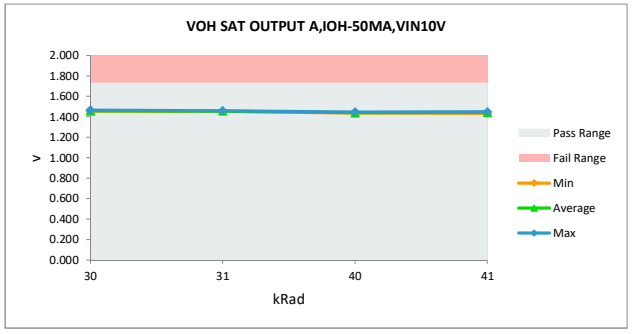
UC1708-SP TID Report

	VOH SAT OUTPUT A,IOH-50MA,VIN10V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	1.73	1.73
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.374	1.461	-0.087
30	11	1.365	1.466	-0.101
30	20	1.359	1.455	-0.096
30	14	1.362	1.457	-0.095
30	19	1.361	1.456	-0.095
40	17	1.363	1.436	-0.073
40	5	1.358	1.442	-0.084
40	13	1.362	1.442	-0.081
40	4	1.367	1.437	-0.070
40	9	1.362	1.447	-0.085
31	3	1.368	1.459	-0.091
31	6	1.359	1.454	-0.095
31	8	1.357	1.456	-0.099
31	10	1.362	1.455	-0.094
31	15	1.366	1.459	-0.092
41	16	1.365	1.439	-0.074
41	18	1.365	1.445	-0.080
41	7	1.362	1.447	-0.085
41	2	1.438	1.435	0.003
41	12	1.362	1.449	-0.087
	Max	1.438	1.466	0.003
	Average	1.367	1.450	-0.083
	Min	1.357	1.435	-0.101
	Std Dev	0.017	0.009	0.022

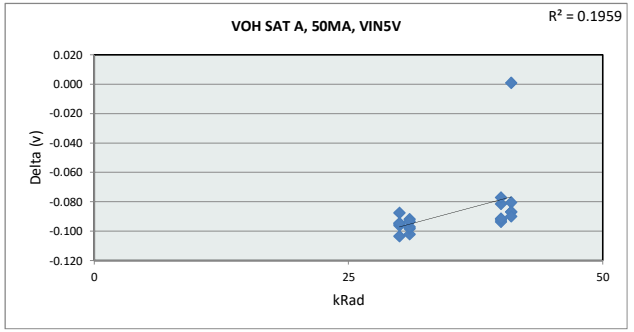


	VOH SAT OUTPUT A,IOH-50MA,VIN			
Test Site				
Tester				
Test Number				
Max Limit	1.73	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.455	1.454	1.436	1.435
Average	1.459	1.457	1.441	1.443
Max	1.466	1.459	1.447	1.449
UL	1.730	1.730	1.730	1.730

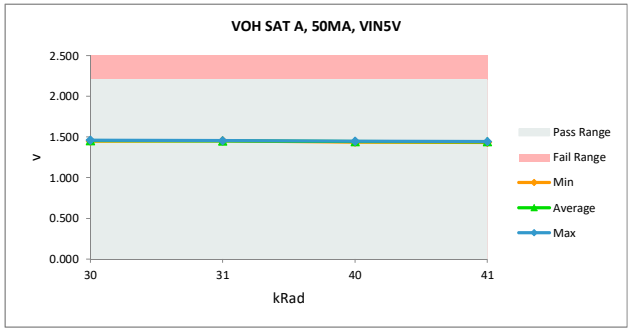


UC1708-SP TID Report

	VOH SAT A, 50MA, VIN5V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	2.2	2.2	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.371	1.458	-0.087
30	11	1.357	1.461	-0.104
30	20	1.355	1.451	-0.096
30	14	1.356	1.451	-0.095
30	19	1.354	1.449	-0.095
40	17	1.357	1.439	-0.082
40	5	1.353	1.445	-0.092
40	13	1.351	1.444	-0.094
40	4	1.361	1.438	-0.077
40	9	1.355	1.447	-0.092
31	3	1.360	1.452	-0.092
31	6	1.353	1.455	-0.102
31	8	1.354	1.452	-0.098
31	10	1.355	1.452	-0.097
31	15	1.357	1.451	-0.093
41	16	1.359	1.439	-0.081
41	18	1.357	1.444	-0.087
41	7	1.357	1.444	-0.087
41	2	1.434	1.433	0.001
41	12	1.355	1.445	-0.090
	Max	1.434	1.461	0.001
	Average	1.361	1.448	-0.087
	Min	1.351	1.433	-0.104
	Std Dev	0.018	0.007	0.022



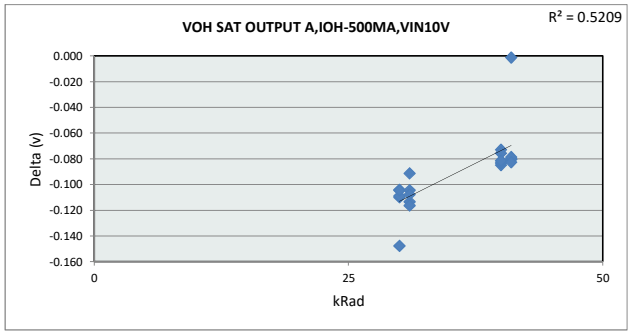
	VOH SAT A, 50MA, VIN5V			
Test Site				
Tester				
Test Number				
Max Limit	2.2	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.449	1.451	1.438	1.433
Average	1.454	1.452	1.443	1.441
Max	1.461	1.455	1.447	1.445
UL	2.200	2.200	2.200	2.200



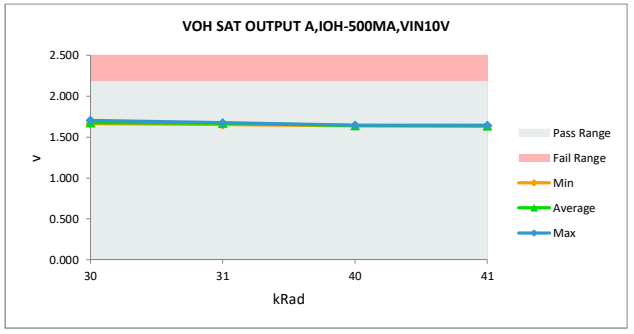
UC1708-SP TID Report

	VOH SAT OUTPUT A,IOH-500MA,VIN10V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	2.18	2.18
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.572	1.681	-0.110
30	11	1.557	1.705	-0.148
30	20	1.563	1.667	-0.104
30	14	1.563	1.671	-0.109
30	19	1.562	1.667	-0.104
40	17	1.567	1.640	-0.073
40	5	1.560	1.645	-0.085
40	13	1.557	1.640	-0.083
40	4	1.564	1.640	-0.076
40	9	1.564	1.646	-0.081
31	3	1.566	1.671	-0.104
31	6	1.561	1.652	-0.091
31	8	1.562	1.676	-0.113
31	10	1.566	1.674	-0.108
31	15	1.560	1.676	-0.116
41	16	1.557	1.637	-0.080
41	18	1.557	1.637	-0.080
41	7	1.562	1.641	-0.079
41	2	1.632	1.633	-0.001
41	12	1.563	1.646	-0.083
	Max	1.632	1.705	-0.001
	Average	1.566	1.657	-0.091
	Min	1.557	1.633	-0.148
	Std Dev	0.016	0.020	0.028

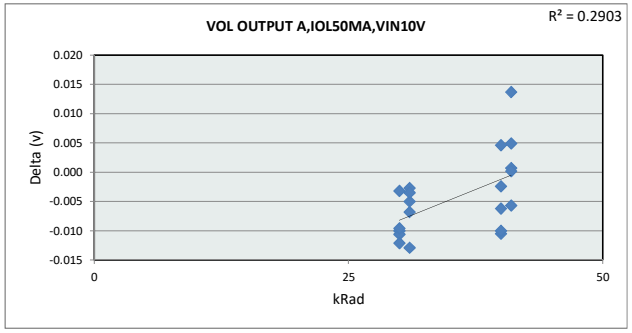


	VOH SAT OUTPUT A,IOH-500MA,V			
Test Site				
Tester				
Test Number				
Max Limit	2.18	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.667	1.652	1.640	1.633
Average	1.678	1.670	1.642	1.639
Max	1.705	1.676	1.646	1.646
UL	2.180	2.180	2.180	2.180

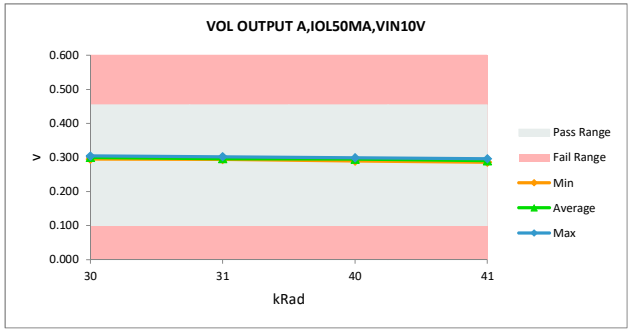


UC1708-SP TID Report

	VOL OUTPUT A,IOL50MA,VIN10V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	0.455	0.455	
Min Limit	0.1	0.1	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.294	0.304	-0.010
30	11	0.292	0.302	-0.011
30	20	0.289	0.301	-0.012
30	14	0.292	0.295	-0.003
30	19	0.289	0.298	-0.010
40	17	0.289	0.296	-0.006
40	5	0.291	0.293	-0.002
40	13	0.287	0.297	-0.011
40	4	0.294	0.289	0.005
40	9	0.289	0.299	-0.010
31	3	0.290	0.295	-0.005
31	6	0.289	0.302	-0.013
31	8	0.290	0.297	-0.007
31	10	0.292	0.295	-0.003
31	15	0.291	0.294	-0.003
41	16	0.293	0.288	0.005
41	18	0.290	0.296	-0.006
41	7	0.292	0.291	0.001
41	2	0.300	0.286	0.014
41	12	0.292	0.292	0.000
	Max	0.300	0.304	0.014
	Average	0.291	0.296	-0.004
	Min	0.287	0.286	-0.013
	Std Dev	0.003	0.005	0.007

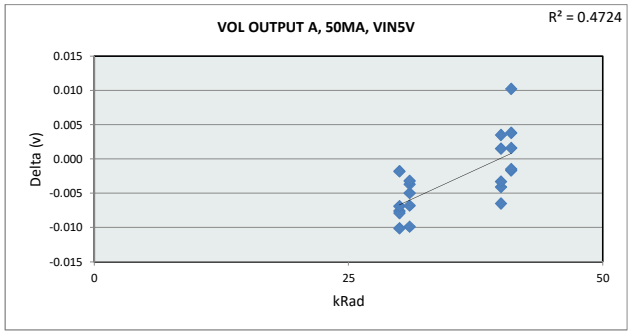


	VOL OUTPUT A,IOL50MA,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	0.455	v		
Min Limit	0.1	v		
kRad	30	31	40	41
LL	0.100	0.100	0.100	0.100
Min	0.295	0.294	0.289	0.286
Average	0.300	0.297	0.295	0.291
Max	0.304	0.302	0.299	0.296
UL	0.455	0.455	0.455	0.455

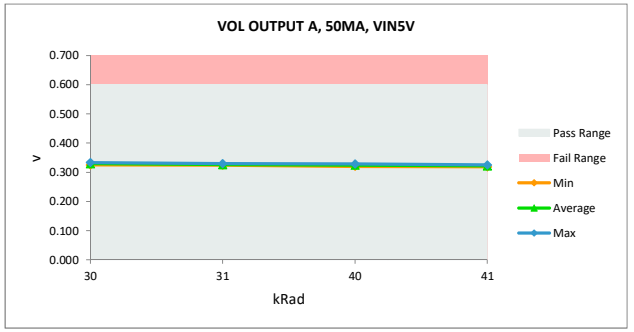


UC1708-SP TID Report

	VOL OUTPUT A, 50MA, VIN5V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	0.6	0.6	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.323	0.333	-0.010
30	11	0.321	0.329	-0.008
30	20	0.322	0.329	-0.008
30	14	0.323	0.325	-0.002
30	19	0.323	0.330	-0.007
40	17	0.322	0.326	-0.004
40	5	0.324	0.322	0.002
40	13	0.322	0.329	-0.007
40	4	0.324	0.320	0.003
40	9	0.323	0.326	-0.003
31	3	0.321	0.326	-0.005
31	6	0.320	0.330	-0.010
31	8	0.320	0.327	-0.007
31	10	0.322	0.326	-0.004
31	15	0.321	0.324	-0.003
41	16	0.323	0.319	0.004
41	18	0.323	0.325	-0.002
41	7	0.325	0.323	0.002
41	2	0.329	0.319	0.010
41	12	0.321	0.322	-0.002
	Max	0.329	0.333	0.010
	Average	0.323	0.326	-0.003
	Min	0.320	0.319	-0.010
	Std Dev	0.002	0.004	0.005

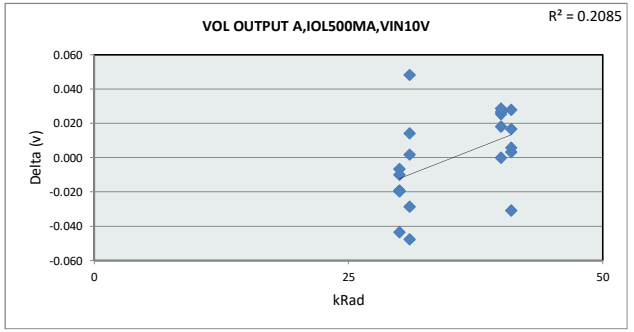


	VOL OUTPUT A, 50MA, VIN5V			
Test Site				
Tester				
Test Number				
Max Limit	0.6	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.325	0.324	0.320	0.319
Average	0.329	0.327	0.325	0.322
Max	0.333	0.330	0.329	0.325
UL	0.600	0.600	0.600	0.600

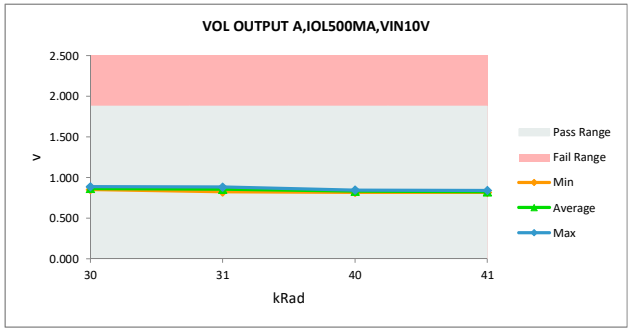


UC1708-SP TID Report

	VOL OUTPUT A,IOL500MA,VIN10V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	1.88	1.88	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.843	0.862	-0.019
30	11	0.844	0.888	-0.044
30	20	0.860	0.867	-0.007
30	14	0.842	0.852	-0.010
30	19	0.844	0.863	-0.020
40	17	0.854	0.829	0.025
40	5	0.847	0.847	0.000
40	13	0.845	0.818	0.027
40	4	0.855	0.837	0.018
40	9	0.864	0.835	0.029
31	3	0.873	0.825	0.048
31	6	0.860	0.846	0.014
31	8	0.853	0.882	-0.029
31	10	0.848	0.846	0.002
31	15	0.836	0.884	-0.048
41	16	0.842	0.825	0.017
41	18	0.830	0.827	0.003
41	7	0.845	0.817	0.028
41	2	0.793	0.824	-0.031
41	12	0.849	0.843	0.006
Max		0.873	0.888	0.048
Average		0.846	0.846	0.001
Min		0.793	0.817	-0.048
Std Dev		0.016	0.022	0.026

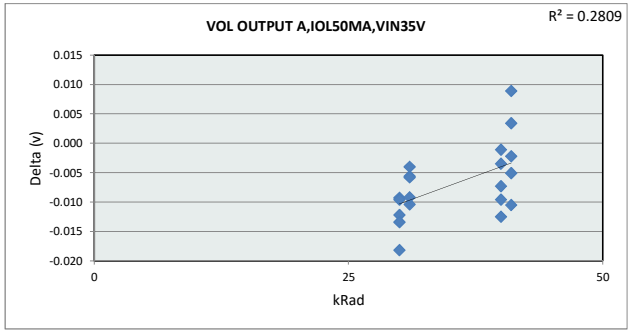


	VOL OUTPUT A,IOL500MA,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	1.88	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.852	0.825	0.818	0.817
Average	0.866	0.856	0.833	0.827
Max	0.888	0.884	0.847	0.843
UL	1.880	1.880	1.880	1.880

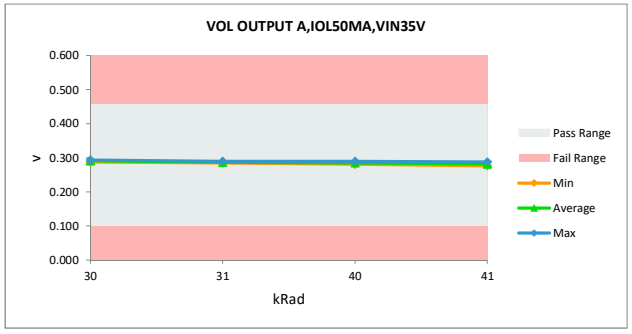


UC1708-SP TID Report

	VOL OUTPUT A,IOL50MA,VIN35V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	0.455	0.455	
Min Limit	0.1	0.1	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.283	0.292	-0.009
30	11	0.280	0.293	-0.012
30	20	0.275	0.293	-0.018
30	14	0.278	0.287	-0.010
30	19	0.277	0.290	-0.013
40	17	0.281	0.288	-0.007
40	5	0.277	0.280	-0.003
40	13	0.276	0.286	-0.010
40	4	0.281	0.282	-0.001
40	9	0.277	0.289	-0.013
31	3	0.280	0.286	-0.006
31	6	0.279	0.289	-0.010
31	8	0.276	0.285	-0.009
31	10	0.282	0.286	-0.004
31	15	0.281	0.287	-0.006
41	16	0.280	0.276	0.003
41	18	0.277	0.287	-0.010
41	7	0.278	0.284	-0.005
41	2	0.286	0.278	0.009
41	12	0.281	0.283	-0.002
	Max	0.286	0.293	0.009
	Average	0.279	0.286	-0.007
	Min	0.275	0.276	-0.018
	Std Dev	0.003	0.005	0.006



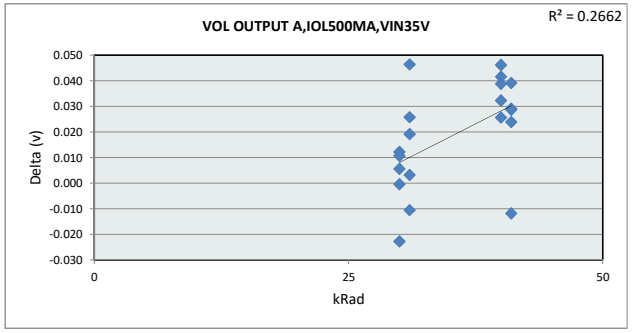
	VOL OUTPUT A,IOL50MA,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	0.455	v		
Min Limit	0.1	v		
kRad	30	31	40	41
LL	0.100	0.100	0.100	0.100
Min	0.287	0.285	0.281	0.276
Average	0.291	0.287	0.285	0.282
Max	0.293	0.289	0.289	0.288
UL	0.455	0.455	0.455	0.455



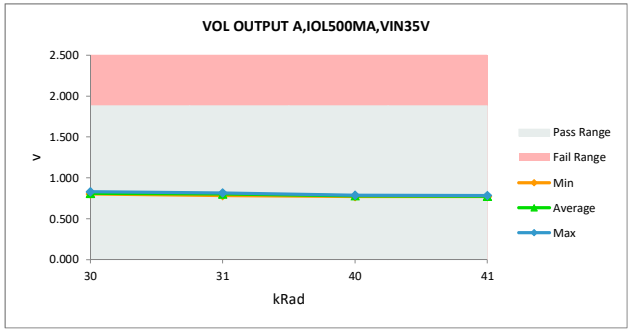
UC1708-SP TID Report

	VOL OUTPUT A,IOL500MA,VIN35V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	1.88	1.88
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.812	0.812	0.000
30	11	0.808	0.831	-0.023
30	20	0.823	0.811	0.012
30	14	0.813	0.802	0.011
30	19	0.811	0.806	0.006
40	17	0.820	0.779	0.042
40	5	0.813	0.787	0.026
40	13	0.810	0.772	0.039
40	4	0.817	0.785	0.032
40	9	0.827	0.781	0.046
31	3	0.829	0.783	0.046
31	6	0.822	0.797	0.026
31	8	0.820	0.817	0.003
31	10	0.814	0.795	0.019
31	15	0.805	0.816	-0.011
41	16	0.805	0.776	0.029
41	18	0.800	0.777	0.024
41	7	0.810	0.771	0.039
41	2	0.762	0.774	-0.012
41	12	0.815	0.785	0.029
Max		0.829	0.831	0.046
Average		0.812	0.793	0.019
Min		0.762	0.771	-0.023
Std Dev		0.014	0.018	0.020

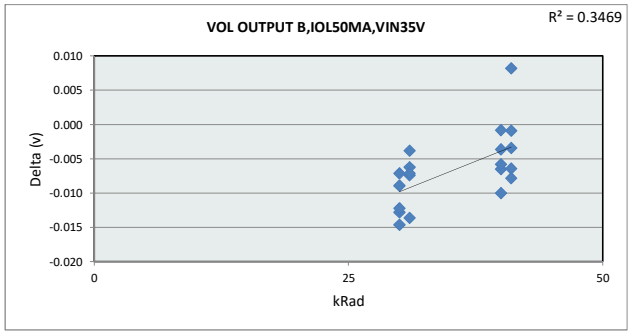


	VOL OUTPUT A,IOL500MA,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	1.88	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.802	0.783	0.772	0.771
Average	0.812	0.802	0.781	0.777
Max	0.831	0.817	0.787	0.786
UL	1.880	1.880	1.880	1.880

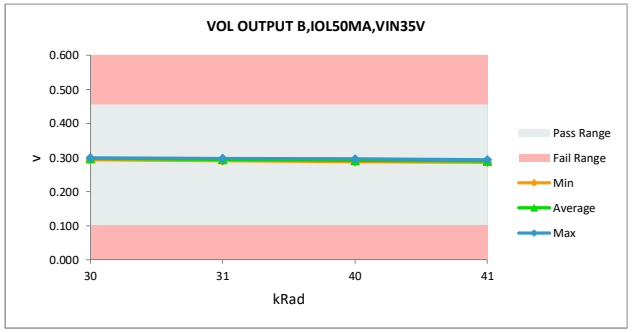


UC1708-SP TID Report

	VOL OUTPUT B,IOL50MA,VIN35V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	0.455	0.455	
Min Limit	0.1	0.1	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.287	0.300	-0.013
30	11	0.286	0.295	-0.009
30	20	0.284	0.299	-0.015
30	14	0.287	0.294	-0.007
30	19	0.287	0.300	-0.012
40	17	0.287	0.293	-0.007
40	5	0.285	0.289	-0.004
40	13	0.286	0.296	-0.010
40	4	0.287	0.288	-0.001
40	9	0.286	0.292	-0.006
31	3	0.289	0.296	-0.007
31	6	0.284	0.298	-0.014
31	8	0.285	0.291	-0.006
31	10	0.287	0.294	-0.007
31	15	0.289	0.293	-0.004
41	16	0.286	0.287	-0.001
41	18	0.287	0.294	-0.006
41	7	0.287	0.290	-0.003
41	2	0.294	0.286	0.008
41	12	0.284	0.292	-0.008
	Max	0.294	0.300	0.008
	Average	0.287	0.293	-0.007
	Min	0.284	0.286	-0.015
	Std Dev	0.002	0.004	0.005

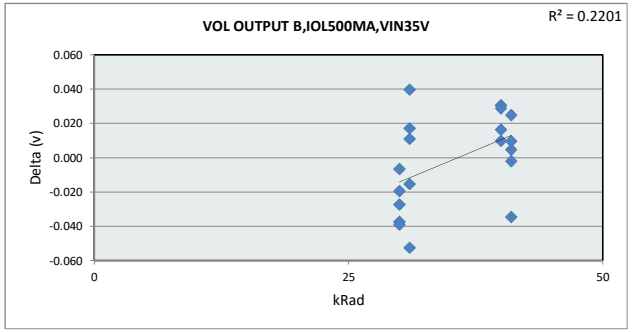


	VOL OUTPUT B,IOL50MA,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	0.455	v		
Min Limit	0.1	v		
kRad	30	31	40	41
LL	0.100	0.100	0.100	0.100
Min	0.294	0.291	0.288	0.286
Average	0.297	0.294	0.292	0.290
Max	0.300	0.298	0.296	0.294
UL	0.455	0.455	0.455	0.455

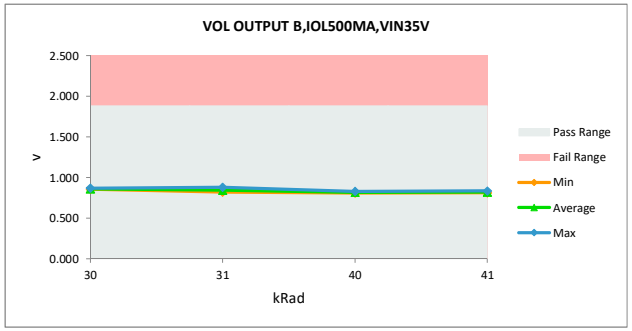


UC1708-SP TID Report

	VOL OUTPUT B,IOL500MA,VIN35V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	1.88	1.88	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.822	0.859	-0.037
30	11	0.845	0.865	-0.019
30	20	0.853	0.859	-0.007
30	14	0.830	0.857	-0.027
30	19	0.831	0.870	-0.039
40	17	0.842	0.812	0.030
40	5	0.840	0.831	0.010
40	13	0.840	0.809	0.030
40	4	0.842	0.826	0.016
40	9	0.844	0.815	0.029
31	3	0.860	0.821	0.040
31	6	0.854	0.837	0.017
31	8	0.843	0.858	-0.015
31	10	0.842	0.831	0.011
31	15	0.829	0.881	-0.053
41	16	0.832	0.822	0.010
41	18	0.821	0.817	0.005
41	7	0.837	0.812	0.025
41	2	0.788	0.822	-0.035
41	12	0.834	0.836	-0.002
	Max	0.860	0.881	0.040
	Average	0.836	0.837	-0.001
	Min	0.788	0.809	-0.053
	Std Dev	0.015	0.022	0.027

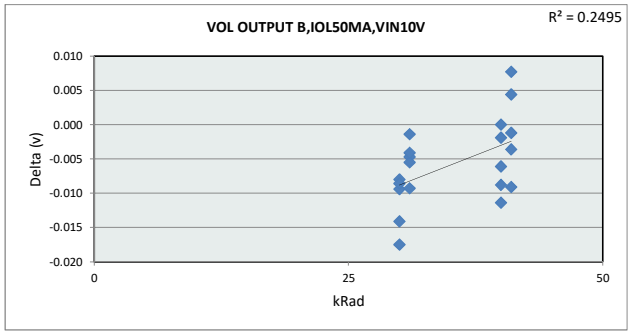


	VOL OUTPUT B,IOL500MA,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	1.88	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.857	0.821	0.810	0.812
Average	0.862	0.846	0.818	0.822
Max	0.870	0.881	0.831	0.836
UL	1.880	1.880	1.880	1.880

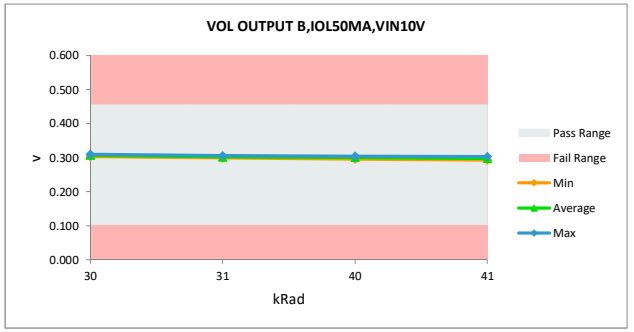


UC1708-SP TID Report

	VOL OUTPUT B,IOL50MA,VIN10V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	0.455	0.455	
Min Limit	0.1	0.1	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.299	0.309	-0.009
30	11	0.299	0.307	-0.008
30	20	0.292	0.310	-0.018
30	14	0.295	0.303	-0.009
30	19	0.293	0.308	-0.014
40	17	0.297	0.303	-0.006
40	5	0.294	0.296	-0.002
40	13	0.294	0.302	-0.009
40	4	0.298	0.298	0.000
40	9	0.293	0.304	-0.011
31	3	0.298	0.303	-0.005
31	6	0.296	0.306	-0.009
31	8	0.294	0.299	-0.006
31	10	0.299	0.301	-0.001
31	15	0.299	0.303	-0.004
41	16	0.297	0.293	0.004
41	18	0.294	0.303	-0.009
41	7	0.296	0.300	-0.004
41	2	0.302	0.294	0.008
41	12	0.297	0.299	-0.001
	Max	0.302	0.310	0.008
	Average	0.296	0.302	-0.006
	Min	0.292	0.293	-0.018
	Std Dev	0.003	0.005	0.006

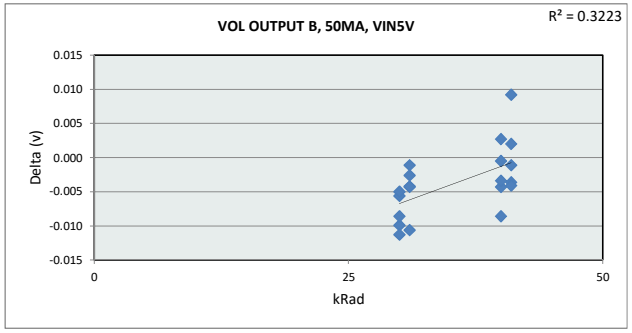


	VOL OUTPUT B,IOL50MA,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	0.455	v		
Min Limit	0.1	v		
kRad	30	31	40	41
LL	0.100	0.100	0.100	0.100
Min	0.304	0.299	0.296	0.293
Average	0.307	0.302	0.301	0.298
Max	0.310	0.306	0.304	0.303
UL	0.455	0.455	0.455	0.455

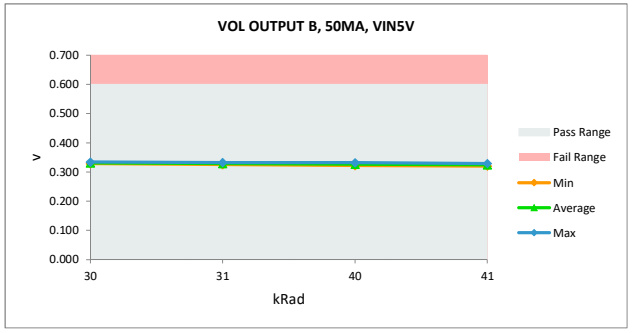


UC1708-SP TID Report

	VOL OUTPUT B, 50MA, VIN5V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	0.6	0.6	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.324	0.334	-0.010
30	11	0.324	0.329	-0.006
30	20	0.321	0.332	-0.011
30	14	0.324	0.329	-0.005
30	19	0.325	0.333	-0.009
40	17	0.324	0.328	-0.004
40	5	0.323	0.323	0.000
40	13	0.323	0.332	-0.009
40	4	0.325	0.322	0.003
40	9	0.324	0.328	-0.003
31	3	0.327	0.331	-0.004
31	6	0.322	0.332	-0.011
31	8	0.323	0.325	-0.003
31	10	0.324	0.328	-0.004
31	15	0.327	0.328	-0.001
41	16	0.324	0.322	0.002
41	18	0.326	0.329	-0.004
41	7	0.324	0.325	-0.001
41	2	0.329	0.320	0.009
41	12	0.322	0.326	-0.004
	Max	0.329	0.334	0.009
	Average	0.324	0.328	-0.004
	Min	0.321	0.320	-0.011
	Std Dev	0.002	0.004	0.005



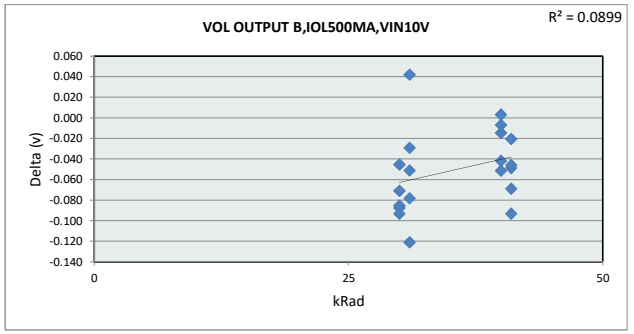
	VOL OUTPUT B, 50MA, VIN5V			
Test Site				
Tester				
Test Number				
Max Limit	0.6	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.329	0.325	0.322	0.320
Average	0.331	0.329	0.327	0.325
Max	0.334	0.332	0.332	0.329
UL	0.600	0.600	0.600	0.600



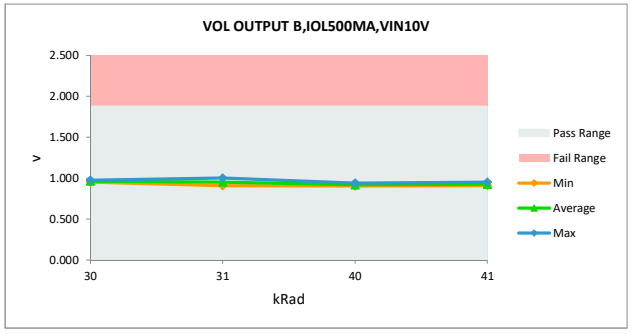
UC1708-SP TID Report

	VOL OUTPUT B,IOL500MA,VIN10V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	1.88	1.88
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.863	0.951	-0.088
30	11	0.898	0.969	-0.071
30	20	0.919	0.964	-0.045
30	14	0.872	0.958	-0.085
30	19	0.882	0.975	-0.093
40	17	0.900	0.908	-0.007
40	5	0.889	0.940	-0.051
40	13	0.896	0.911	-0.015
40	4	0.890	0.932	-0.042
40	9	0.909	0.906	0.003
31	3	0.950	0.908	0.042
31	6	0.910	0.940	-0.029
31	8	0.895	0.973	-0.078
31	10	0.886	0.937	-0.051
31	15	0.882	1.003	-0.121
41	16	0.880	0.929	-0.049
41	18	0.868	0.914	-0.046
41	7	0.889	0.910	-0.021
41	2	0.834	0.927	-0.093
41	12	0.883	0.952	-0.069
	Max	0.950	1.003	0.042
	Average	0.890	0.940	-0.051
	Min	0.834	0.906	-0.121
	Std Dev	0.023	0.027	0.039

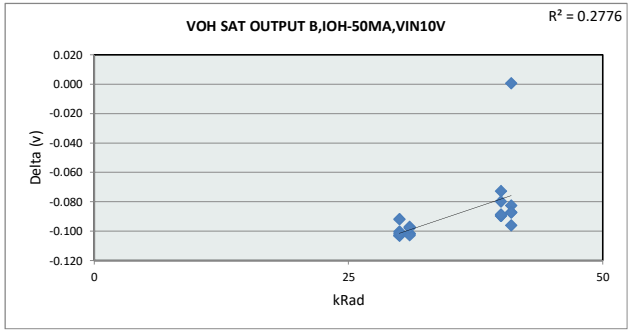


	VOL OUTPUT B,IOL500MA,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	1.88	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	0.951	0.908	0.906	0.910
Average	0.963	0.952	0.919	0.926
Max	0.975	1.003	0.940	0.952
UL	1.880	1.880	1.880	1.880

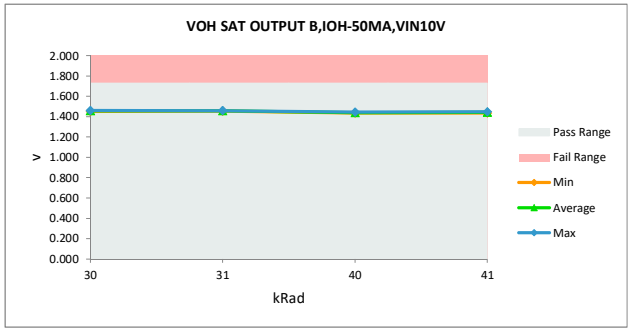


UC1708-SP TID Report

	VOH SAT OUTPUT B,IOH-50MA,VIN10V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	1.73	1.73	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.367	1.459	-0.092
30	11	1.357	1.460	-0.103
30	20	1.352	1.453	-0.100
30	14	1.353	1.456	-0.103
30	19	1.356	1.458	-0.102
40	17	1.355	1.435	-0.080
40	5	1.352	1.442	-0.090
40	13	1.352	1.442	-0.090
40	4	1.362	1.435	-0.073
40	9	1.356	1.445	-0.089
31	3	1.362	1.459	-0.097
31	6	1.352	1.454	-0.102
31	8	1.352	1.454	-0.102
31	10	1.356	1.459	-0.103
31	15	1.361	1.459	-0.098
41	16	1.357	1.440	-0.082
41	18	1.358	1.445	-0.087
41	7	1.357	1.445	-0.087
41	2	1.435	1.435	0.001
41	12	1.353	1.449	-0.096
	Max	1.435	1.460	0.001
	Average	1.360	1.449	-0.089
	Min	1.352	1.435	-0.103
	Std Dev	0.018	0.009	0.023

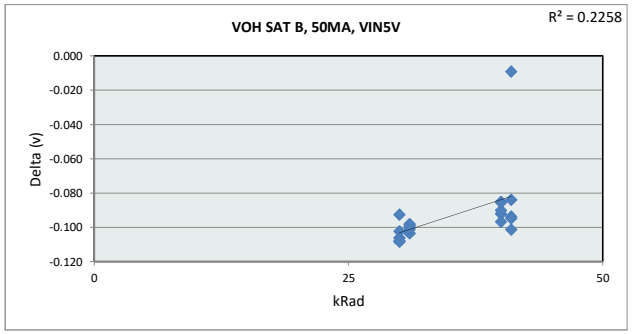


	VOH SAT OUTPUT B,IOH-50MA,VIN			
Test Site				
Tester				
Test Number				
Max Limit	1.73	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.453	1.454	1.435	1.435
Average	1.457	1.457	1.440	1.443
Max	1.460	1.459	1.445	1.449
UL	1.730	1.730	1.730	1.730

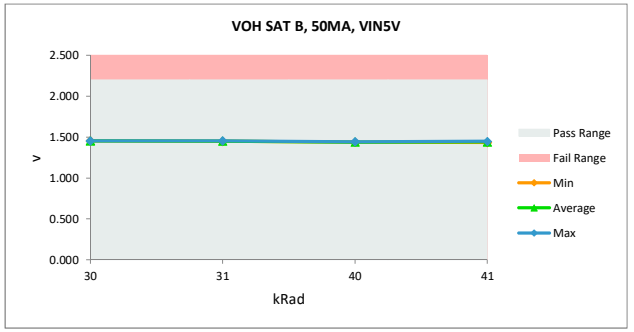


UC1708-SP TID Report

	VOH SAT B, 50MA, VIN5V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	2.2	2.2	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.363	1.455	-0.093
30	11	1.353	1.455	-0.102
30	20	1.348	1.454	-0.106
30	14	1.348	1.456	-0.108
30	19	1.348	1.456	-0.108
40	17	1.354	1.439	-0.085
40	5	1.348	1.440	-0.092
40	13	1.350	1.440	-0.090
40	4	1.354	1.439	-0.085
40	9	1.348	1.444	-0.097
31	3	1.355	1.455	-0.100
31	6	1.351	1.449	-0.098
31	8	1.345	1.449	-0.104
31	10	1.353	1.452	-0.099
31	15	1.354	1.455	-0.101
41	16	1.350	1.434	-0.084
41	18	1.350	1.444	-0.094
41	7	1.351	1.445	-0.095
41	2	1.428	1.437	-0.009
41	12	1.348	1.449	-0.101
	Max	1.428	1.456	-0.009
	Average	1.355	1.447	-0.092
	Min	1.345	1.434	-0.108
	Std Dev	0.018	0.007	0.021



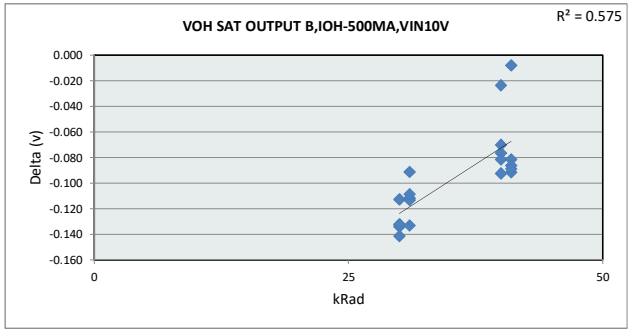
	VOH SAT B, 50MA, VIN5V			
Test Site				
Tester				
Test Number				
Max Limit	2.2	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.454	1.449	1.439	1.434
Average	1.455	1.452	1.441	1.442
Max	1.456	1.455	1.444	1.449
UL	2.200	2.200	2.200	2.200



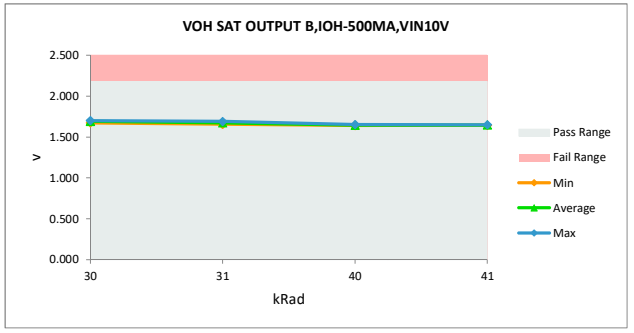
UC1708-SP TID Report

	VOH SAT OUTPUT B,IOH-500MA,VIN10V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	2.18	2.18
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.567	1.700	-0.132
30	11	1.564	1.698	-0.134
30	20	1.561	1.674	-0.113
30	14	1.558	1.690	-0.132
30	19	1.560	1.701	-0.141
40	17	1.564	1.641	-0.077
40	5	1.626	1.649	-0.023
40	13	1.561	1.642	-0.081
40	4	1.571	1.641	-0.070
40	9	1.560	1.652	-0.092
31	3	1.567	1.679	-0.112
31	6	1.564	1.656	-0.091
31	8	1.557	1.670	-0.113
31	10	1.567	1.676	-0.109
31	15	1.558	1.691	-0.133
41	16	1.562	1.644	-0.081
41	18	1.557	1.649	-0.091
41	7	1.562	1.649	-0.086
41	2	1.636	1.644	-0.008
41	12	1.561	1.650	-0.089
	Max	1.636	1.701	-0.008
	Average	1.569	1.665	-0.095
	Min	1.557	1.641	-0.141
	Std Dev	0.021	0.022	0.035

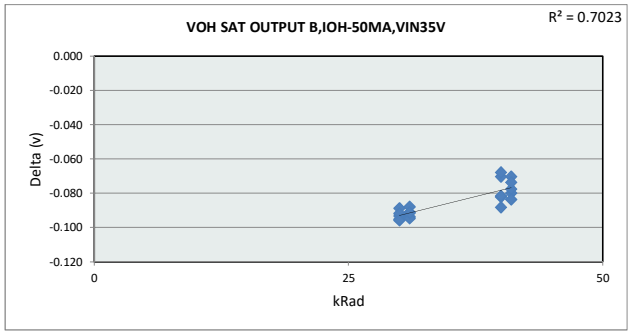


	VOH SAT OUTPUT B,IOH-500MA,V			
Test Site				
Tester				
Test Number				
Max Limit	2.18	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.674	1.656	1.641	1.644
Average	1.693	1.674	1.645	1.647
Max	1.701	1.691	1.652	1.650
UL	2.180	2.180	2.180	2.180

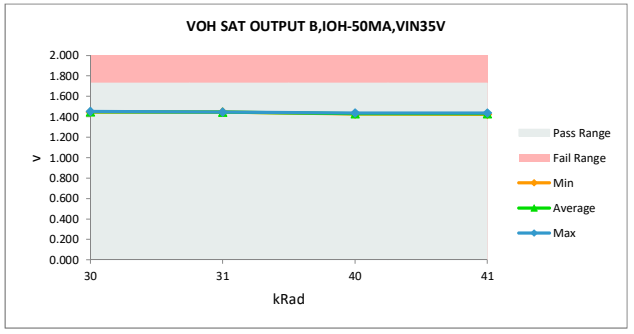


UC1708-SP TID Report

	VOH SAT OUTPUT B,IOH-50MA,VIN35V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	1.73	1.73	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.363	1.452	-0.089
30	11	1.357	1.451	-0.093
30	20	1.350	1.445	-0.095
30	14	1.353	1.445	-0.092
30	19	1.351	1.447	-0.096
40	17	1.356	1.426	-0.070
40	5	1.351	1.434	-0.082
40	13	1.349	1.431	-0.082
40	4	1.358	1.426	-0.068
40	9	1.349	1.437	-0.088
31	3	1.358	1.446	-0.088
31	6	1.351	1.445	-0.094
31	8	1.351	1.446	-0.095
31	10	1.354	1.445	-0.091
31	15	1.354	1.445	-0.092
41	16	1.356	1.426	-0.070
41	18	1.354	1.434	-0.080
41	7	1.356	1.434	-0.078
41	2	1.349	1.423	-0.074
41	12	1.354	1.437	-0.084
	Max	1.363	1.452	-0.068
	Average	1.354	1.439	-0.085
	Min	1.349	1.423	-0.096
	Std Dev	0.004	0.009	0.009



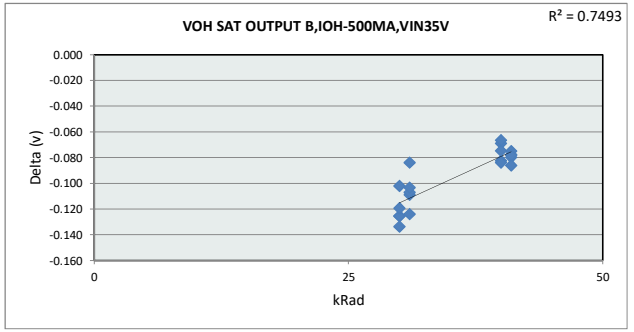
	VOH SAT OUTPUT B,IOH-50MA,VIN			
Test Site				
Tester				
Test Number				
Max Limit	1.73	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.445	1.445	1.426	1.423
Average	1.448	1.445	1.431	1.431
Max	1.452	1.446	1.437	1.437
UL	1.730	1.730	1.730	1.730



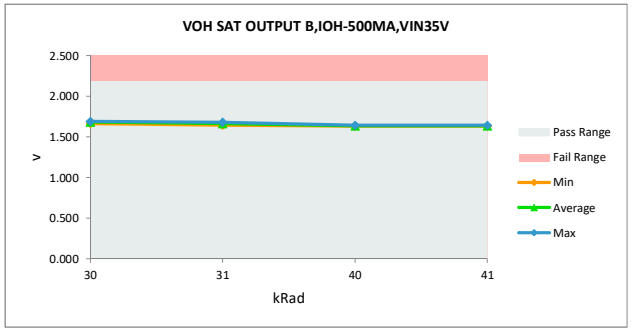
UC1708-SP TID Report

	VOH SAT OUTPUT B,IOH-500MA,VIN35V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	2.18	2.18
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.564	1.689	-0.125
30	11	1.564	1.689	-0.125
30	20	1.562	1.664	-0.102
30	14	1.559	1.678	-0.119
30	19	1.558	1.691	-0.134
40	17	1.564	1.633	-0.069
40	5	1.559	1.641	-0.082
40	13	1.559	1.633	-0.075
40	4	1.566	1.633	-0.066
40	9	1.559	1.642	-0.084
31	3	1.561	1.670	-0.109
31	6	1.561	1.645	-0.084
31	8	1.555	1.662	-0.107
31	10	1.564	1.667	-0.103
31	15	1.558	1.681	-0.124
41	16	1.558	1.636	-0.078
41	18	1.554	1.634	-0.080
41	7	1.561	1.636	-0.075
41	2	1.554	1.633	-0.078
41	12	1.558	1.643	-0.086
	Max	1.566	1.691	-0.066
	Average	1.560	1.655	-0.095
	Min	1.554	1.633	-0.134
	Std Dev	0.003	0.022	0.022

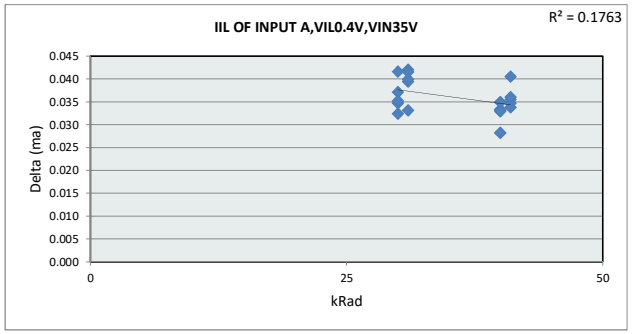


	VOH SAT OUTPUT B,IOH-500MA,V			
Test Site				
Tester				
Test Number				
Max Limit	2.18	v		
Min Limit	0	v		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	1.664	1.645	1.633	1.633
Average	1.682	1.665	1.636	1.636
Max	1.691	1.681	1.642	1.644
UL	2.180	2.180	2.180	2.180

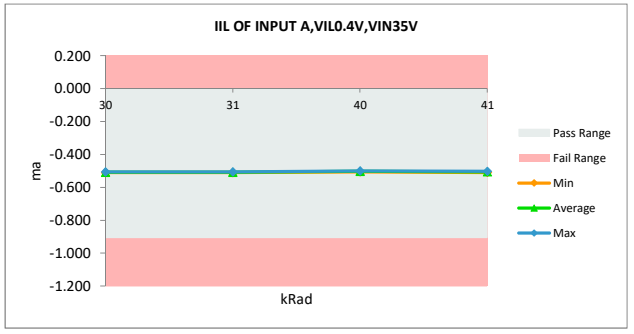


UC1708-SP TID Report

	IIL OF INPUT A,VIL0.4V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	-0.0001	-0.0001	
Min Limit	-0.905	-0.905	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-0.475	-0.510	0.035
30	11	-0.470	-0.507	0.037
30	20	-0.474	-0.506	0.032
30	14	-0.469	-0.511	0.042
30	19	-0.472	-0.507	0.035
40	17	-0.468	-0.501	0.033
40	5	-0.471	-0.504	0.033
40	13	-0.472	-0.501	0.028
40	4	-0.467	-0.502	0.035
40	9	-0.473	-0.506	0.033
31	3	-0.469	-0.511	0.042
31	6	-0.472	-0.506	0.033
31	8	-0.469	-0.510	0.042
31	10	-0.468	-0.508	0.039
31	15	-0.470	-0.510	0.040
41	16	-0.469	-0.505	0.036
41	18	-0.472	-0.507	0.035
41	7	-0.469	-0.509	0.041
41	2	-0.471	-0.504	0.034
41	12	-0.467	-0.503	0.036
Max		-0.467	-0.501	0.042
Average		-0.470	-0.506	0.036
Min		-0.475	-0.511	0.028
Std Dev		0.002	0.003	0.004

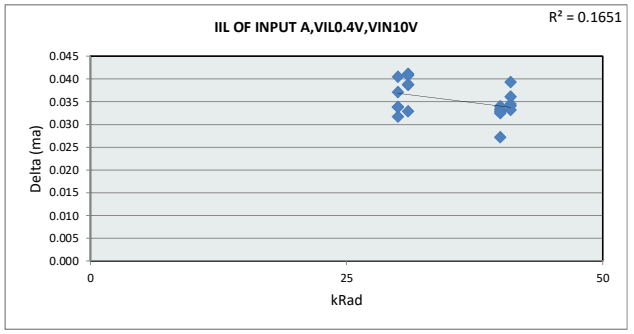


	IIL OF INPUT A,VIL0.4V,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	-0.0001	ma		
Min Limit	-0.905	ma		
kRad	30	31	40	41
LL	-0.905	-0.905	-0.905	-0.905
Min	-0.511	-0.511	-0.506	-0.509
Average	-0.508	-0.509	-0.503	-0.506
Max	-0.506	-0.506	-0.501	-0.503
UL	0.000	0.000	0.000	0.000

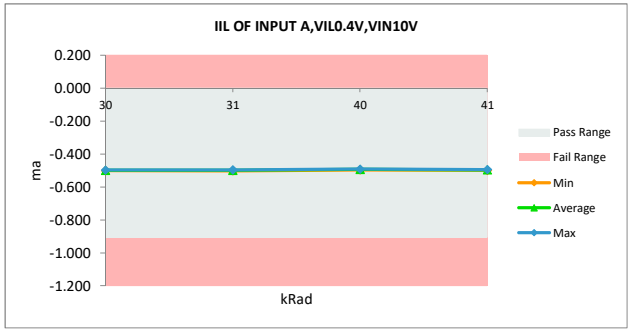


UC1708-SP TID Report

	IIL OF INPUT A,VIL0.4V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	-0.0001	-0.0001	
Min Limit	-0.905	-0.905	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-0.466	-0.499	0.034
30	11	-0.460	-0.497	0.037
30	20	-0.465	-0.496	0.032
30	14	-0.460	-0.501	0.040
30	19	-0.463	-0.496	0.034
40	17	-0.458	-0.491	0.033
40	5	-0.462	-0.495	0.033
40	13	-0.463	-0.490	0.027
40	4	-0.458	-0.492	0.034
40	9	-0.463	-0.496	0.032
31	3	-0.460	-0.501	0.041
31	6	-0.463	-0.495	0.033
31	8	-0.459	-0.500	0.041
31	10	-0.459	-0.498	0.039
31	15	-0.461	-0.499	0.039
41	16	-0.460	-0.495	0.035
41	18	-0.463	-0.497	0.034
41	7	-0.460	-0.499	0.039
41	2	-0.461	-0.495	0.033
41	12	-0.457	-0.493	0.036
	Max	-0.457	-0.490	0.041
	Average	-0.461	-0.496	0.035
	Min	-0.466	-0.501	0.027
	Std Dev	0.002	0.003	0.004

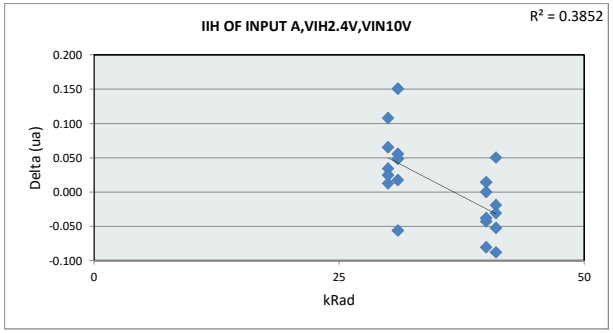


	IIL OF INPUT A,VIL0.4V,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	-0.0001	ma		
Min Limit	-0.905	ma		
kRad	30	31	40	41
LL	-0.905	-0.905	-0.905	-0.905
Min	-0.501	-0.501	-0.496	-0.499
Average	-0.498	-0.499	-0.493	-0.496
Max	-0.496	-0.496	-0.490	-0.493
UL	0.000	0.000	0.000	0.000

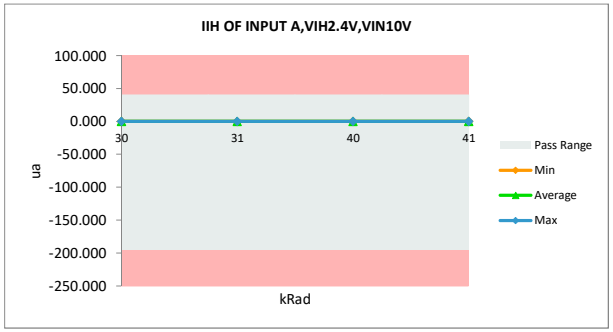


UC1708-SP TID Report

	IIH OF INPUT A,VIH2.4V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	40	40	
Min Limit	-195	-195	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.133	0.067	0.065
30	11	0.149	0.041	0.108
30	20	0.080	0.067	0.013
30	14	0.085	0.051	0.034
30	19	0.123	0.098	0.025
40	17	0.078	0.159	-0.080
40	5	0.107	0.149	-0.042
40	13	0.133	0.170	-0.038
40	4	0.195	0.180	0.015
40	9	0.149	0.149	0.000
31	3	0.145	0.096	0.049
31	6	0.152	0.001	0.151
31	8	0.080	0.136	-0.056
31	10	0.097	0.041	0.056
31	15	0.078	0.060	0.018
41	16	0.199	0.149	0.050
41	18	0.152	0.170	-0.019
41	7	0.119	0.206	-0.088
41	2	0.133	0.185	-0.052
41	12	0.116	0.147	-0.030
	Max	0.199	0.206	0.151
	Average	0.125	0.116	0.009
	Min	0.078	0.001	-0.088
	Std Dev	0.036	0.059	0.062

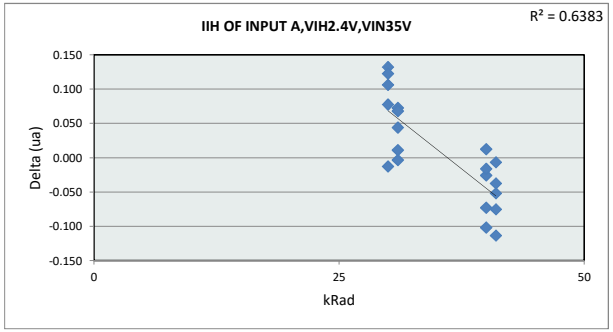


	IIH OF INPUT A,VIH2.4V,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	40	ua		
Min Limit	-195	ua		
kRad	30	31	40	41
LL	-195.000	-195.000	-195.000	-195.000
Min	0.041	0.001	0.149	0.147
Average	0.065	0.067	0.161	0.171
Max	0.098	0.136	0.180	0.206
UL	40.000	40.000	40.000	40.000

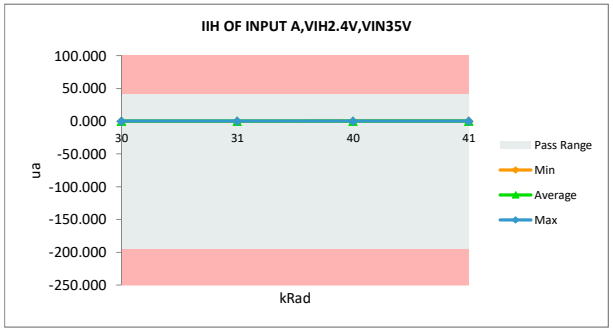


UC1708-SP TID Report

	IIH OF INPUT A,VIH2.4V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	40	40	
Min Limit	-195	-195	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.097	-0.009	0.106
30	11	0.097	-0.035	0.132
30	20	0.123	0.001	0.122
30	14	0.097	0.020	0.077
30	19	0.038	0.051	-0.013
40	17	0.123	0.111	0.012
40	5	0.078	0.104	-0.026
40	13	0.047	0.149	-0.102
40	4	0.078	0.094	-0.016
40	9	0.021	0.094	-0.073
31	3	0.038	0.041	-0.003
31	6	0.114	0.041	0.073
31	8	0.047	-0.021	0.068
31	10	0.073	0.029	0.044
31	15	0.031	0.020	0.011
41	16	0.073	0.111	-0.038
41	18	0.035	0.149	-0.114
41	7	0.078	0.130	-0.052
41	2	0.123	0.130	-0.007
41	12	0.035	0.111	-0.076
Max		0.123	0.149	0.132
Average		0.072	0.066	0.006
Min		0.021	-0.035	-0.114
Std Dev		0.034	0.059	0.073

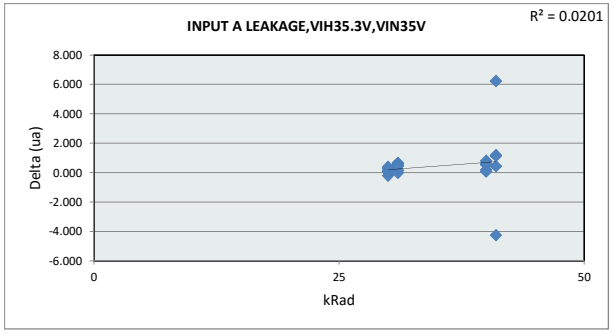


	IIH OF INPUT A,VIH2.4V,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	40	ua		
Min Limit	-195	ua		
kRad	30	31	40	41
LL	-195.000	-195.000	-195.000	-195.000
Min	-0.035	-0.021	0.094	0.111
Average	0.005	0.022	0.110	0.126
Max	0.051	0.041	0.149	0.149
UL	40.000	40.000	40.000	40.000

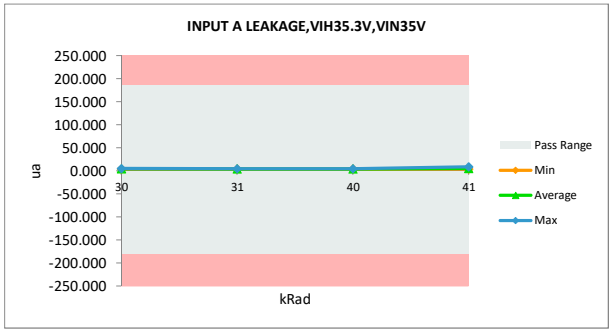


UC1708-SP TID Report

	INPUT A LEAKAGE,VIH35.3V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	185	185	
Min Limit	-180	-180	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	4.854	5.064	-0.210
30	11	4.682	4.389	0.294
30	20	4.530	4.389	0.141
30	14	4.419	4.370	0.049
30	19	4.628	4.248	0.379
40	17	4.343	4.151	0.192
40	5	4.476	4.398	0.077
40	13	4.894	4.094	0.800
40	4	4.571	4.023	0.548
40	9	4.495	3.906	0.589
31	3	4.759	4.108	0.650
31	6	4.476	4.313	0.163
31	8	4.419	4.429	-0.011
31	10	4.504	3.951	0.553
31	15	4.435	3.987	0.448
41	16	4.549	8.805	-4.255
41	18	4.737	4.303	0.434
41	7	4.977	3.789	1.188
41	2	4.897	3.754	1.143
41	12	10.258	4.027	6.231
Max		10.258	8.805	6.231
Average		4.895	4.425	0.470
Min		4.343	3.754	-4.255
Std Dev		1.276	1.071	1.747

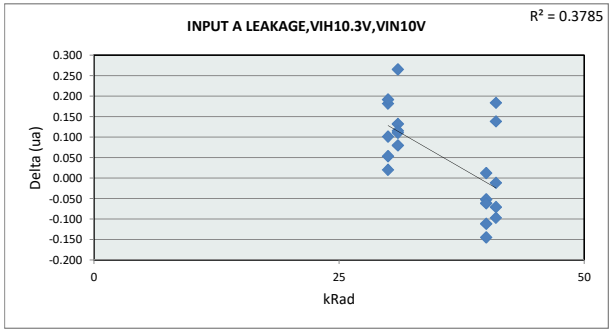


	INPUT A LEAKAGE,VIH35.3V,VIN3			
Test Site				
Tester				
Test Number				
Max Limit	185	ua		
Min Limit	-180	ua		
kRad	30	31	40	41
LL	-180.000	-180.000	-180.000	-180.000
Min	4.248	3.951	3.906	3.754
Average	4.492	4.158	4.114	4.936
Max	5.064	4.429	4.398	8.805
UL	185.000	185.000	185.000	185.000

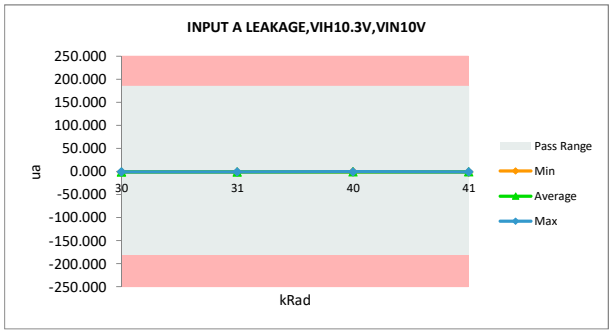


UC1708-SP TID Report

	INPUT A LEAKAGE,VIH10.3V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	185	185	
Min Limit	-180	-180	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-0.642	-0.663	0.020
30	11	-0.609	-0.663	0.054
30	20	-0.664	-0.846	0.182
30	14	-0.609	-0.710	0.101
30	19	-0.552	-0.744	0.192
40	17	-0.721	-0.576	-0.144
40	5	-0.664	-0.612	-0.052
40	13	-0.616	-0.555	-0.061
40	4	-0.562	-0.574	0.012
40	9	-0.571	-0.460	-0.111
31	3	-0.628	-0.760	0.132
31	6	-0.588	-0.703	0.115
31	8	-0.664	-0.744	0.080
31	10	-0.588	-0.698	0.111
31	15	-0.571	-0.836	0.265
41	16	-0.552	-0.690	0.138
41	18	-0.609	-0.538	-0.071
41	7	-0.642	-0.631	-0.012
41	2	-0.688	-0.590	-0.097
41	12	-0.571	-0.755	0.184
	Max	-0.552	-0.460	0.265
	Average	-0.616	-0.667	0.052
	Min	-0.721	-0.846	-0.144
	Std Dev	0.048	0.101	0.116

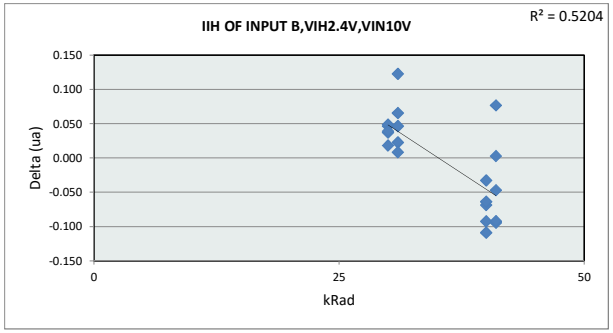


	INPUT A LEAKAGE,VIH10.3V,VIN1			
Test Site				
Tester				
Test Number				
Max Limit	185	ua		
Min Limit	-180	ua		
kRad	30	31	40	41
LL	-180.000	-180.000	-180.000	-180.000
Min	-0.846	-0.836	-0.612	-0.755
Average	-0.725	-0.748	-0.555	-0.641
Max	-0.663	-0.699	-0.460	-0.538
UL	185.000	185.000	185.000	185.000

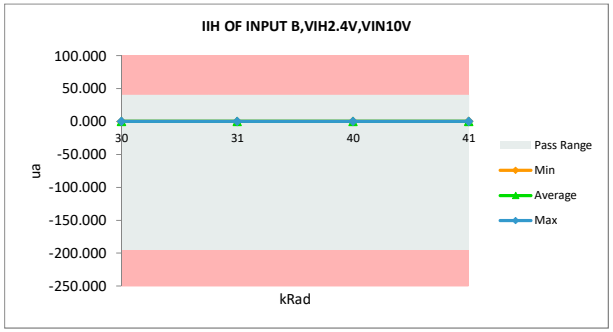


UC1708-SP TID Report

	IIH OF INPUT B,VIH2.4V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	40	40	
Min Limit	-195	-195	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.057	0.020	0.037
30	11	0.123	0.077	0.046
30	20	0.078	0.029	0.049
30	14	0.099	0.060	0.039
30	19	0.038	0.020	0.018
40	17	0.080	0.149	-0.069
40	5	0.119	0.151	-0.033
40	13	0.021	0.130	-0.109
40	4	0.133	0.197	-0.064
40	9	0.114	0.206	-0.092
31	3	0.097	0.051	0.046
31	6	0.107	0.041	0.065
31	8	0.123	0.001	0.122
31	10	0.085	0.063	0.023
31	15	0.085	0.077	0.008
41	16	0.192	0.116	0.077
41	18	0.097	0.192	-0.095
41	7	0.145	0.192	-0.047
41	2	0.097	0.189	-0.092
41	12	0.152	0.149	0.003
	Max	0.192	0.206	0.122
	Average	0.102	0.105	-0.003
	Min	0.021	0.001	-0.109
	Std Dev	0.039	0.069	0.067

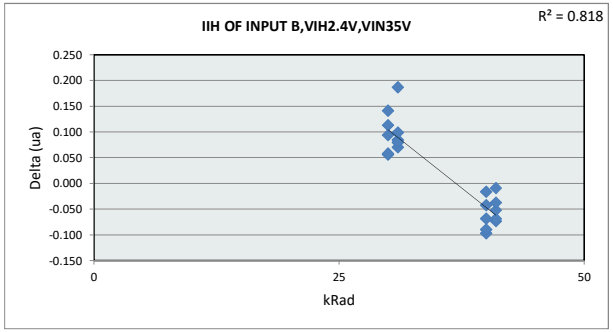


	IIH OF INPUT B,VIH2.4V,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	40	ua		
Min Limit	-195	ua		
kRad	30	31	40	41
LL	-195.000	-195.000	-195.000	-195.000
Min	0.020	0.001	0.130	0.116
Average	0.041	0.046	0.167	0.168
Max	0.077	0.077	0.206	0.192
UL	40.000	40.000	40.000	40.000

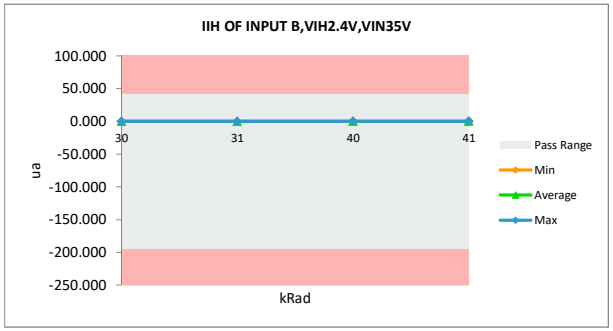


UC1708-SP TID Report

	IIH OF INPUT B,VIH2.4V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	40	40	
Min Limit	-195	-195	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.123	-0.018	0.141
30	11	0.085	0.029	0.056
30	20	0.114	0.001	0.113
30	14	0.114	0.020	0.094
30	19	0.078	0.020	0.058
40	17	0.133	0.149	-0.016
40	5	0.107	0.149	-0.042
40	13	0.073	0.170	-0.097
40	4	0.031	0.120	-0.090
40	9	0.085	0.154	-0.068
31	3	0.085	0.001	0.084
31	6	0.111	0.041	0.070
31	8	0.133	-0.054	0.187
31	10	0.123	0.043	0.080
31	15	0.111	0.013	0.099
41	16	0.057	0.130	-0.073
41	18	0.080	0.149	-0.069
41	7	0.097	0.149	-0.052
41	2	0.133	0.170	-0.038
41	12	0.149	0.159	-0.009
	Max	0.149	0.170	0.187
	Average	0.101	0.080	0.021
	Min	0.031	-0.054	-0.097
	Std Dev	0.029	0.076	0.086

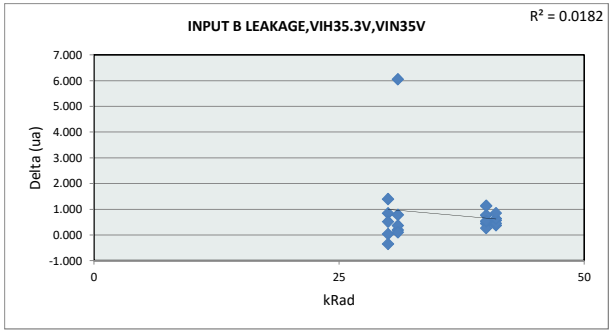


	IIH OF INPUT B,VIH2.4V,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	40	ua		
Min Limit	-195	ua		
kRad	30	31	40	41
LL	-195.000	-195.000	-195.000	-195.000
Min	-0.018	-0.054	0.120	0.130
Average	0.010	0.009	0.149	0.151
Max	0.029	0.044	0.170	0.170
UL	40.000	40.000	40.000	40.000

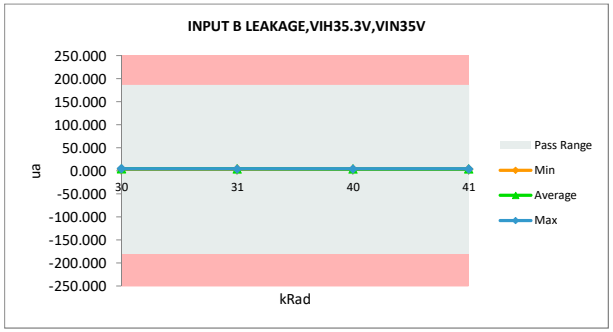


UC1708-SP TID Report

	INPUT B LEAKAGE,VIH35.3V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	185	185	
Min Limit	-180	-180	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	4.911	4.065	0.846
30	11	4.606	4.084	0.522
30	20	5.738	4.341	1.397
30	14	4.549	4.505	0.044
30	19	4.407	4.753	-0.346
40	17	4.673	4.218	0.455
40	5	4.478	4.208	0.270
40	13	4.647	3.875	0.772
40	4	4.951	3.811	1.140
40	9	4.521	3.982	0.539
31	3	10.070	4.008	6.062
31	6	4.397	4.201	0.196
31	8	4.970	4.184	0.786
31	10	4.590	4.220	0.370
31	15	4.209	4.103	0.106
41	16	4.514	3.944	0.570
41	18	4.495	4.115	0.379
41	7	4.483	4.023	0.460
41	2	4.666	4.027	0.639
41	12	4.666	3.811	0.855
	Max	10.070	4.753	6.062
	Average	4.927	4.124	0.803
	Min	4.209	3.811	-0.346
	Std Dev	1.251	0.226	1.298

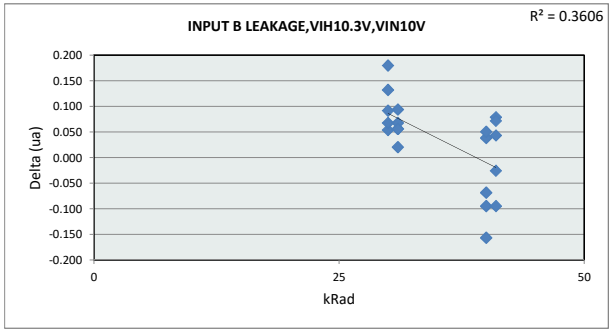


	INPUT B LEAKAGE,VIH35.3V,VIN3			
Test Site				
Tester				
Test Number				
Max Limit	185	ua		
Min Limit	-180	ua		
kRad	30	31	40	41
LL	-180.000	-180.000	-180.000	-180.000
Min	4.065	4.008	3.811	3.811
Average	4.350	4.143	4.019	3.984
Max	4.753	4.220	4.218	4.115
UL	185.000	185.000	185.000	185.000

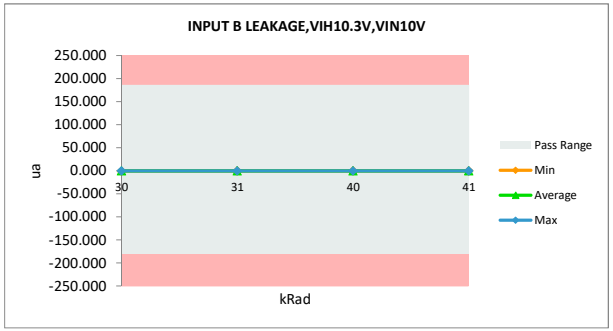


UC1708-SP TID Report

	INPUT B LEAKAGE,VIH10.3V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	185	185	
Min Limit	-180	-180	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-0.616	-0.796	0.180
30	11	-0.609	-0.663	0.054
30	20	-0.571	-0.703	0.132
30	14	-0.642	-0.710	0.068
30	19	-0.552	-0.644	0.092
40	17	-0.645	-0.488	-0.157
40	5	-0.683	-0.614	-0.069
40	13	-0.552	-0.590	0.038
40	4	-0.628	-0.534	-0.095
40	9	-0.552	-0.602	0.050
31	3	-0.571	-0.627	0.056
31	6	-0.642	-0.710	0.068
31	8	-0.616	-0.710	0.094
31	10	-0.683	-0.703	0.021
31	15	-0.664	-0.720	0.056
41	16	-0.628	-0.534	-0.095
41	18	-0.588	-0.667	0.079
41	7	-0.531	-0.574	0.043
41	2	-0.638	-0.612	-0.026
41	12	-0.531	-0.602	0.072
	Max	-0.531	-0.488	0.180
	Average	-0.607	-0.640	0.033
	Min	-0.683	-0.796	-0.157
	Std Dev	0.048	0.077	0.082

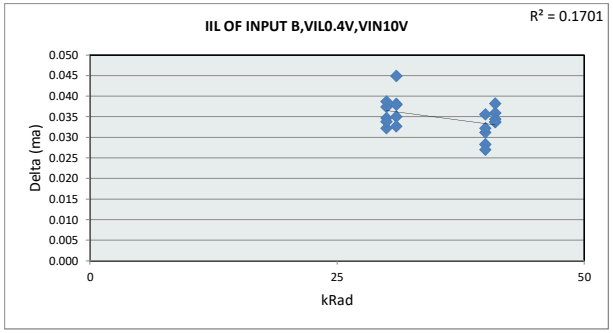


	INPUT B LEAKAGE,VIH10.3V,VIN1			
Test Site				
Tester				
Test Number				
Max Limit	185	ua		
Min Limit	-180	ua		
kRad	30	31	40	41
LL	-180.000	-180.000	-180.000	-180.000
Min	-0.796	-0.720	-0.614	-0.667
Average	-0.703	-0.694	-0.566	-0.598
Max	-0.644	-0.627	-0.488	-0.534
UL	185.000	185.000	185.000	185.000

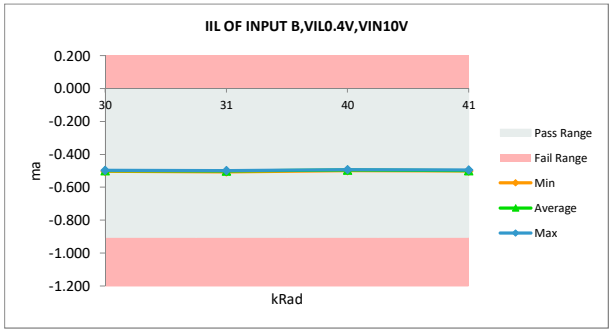


UC1708-SP TID Report

	IIL OF INPUT B,VIL0.4V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	-0.0001	-0.0001	
Min Limit	-0.905	-0.905	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-0.469	-0.501	0.032
30	11	-0.462	-0.499	0.037
30	20	-0.464	-0.498	0.035
30	14	-0.464	-0.502	0.039
30	19	-0.463	-0.497	0.034
40	17	-0.461	-0.493	0.031
40	5	-0.463	-0.498	0.036
40	13	-0.469	-0.497	0.028
40	4	-0.466	-0.493	0.027
40	9	-0.467	-0.499	0.032
31	3	-0.461	-0.506	0.045
31	6	-0.466	-0.501	0.035
31	8	-0.464	-0.502	0.038
31	10	-0.466	-0.498	0.033
31	15	-0.462	-0.500	0.038
41	16	-0.463	-0.497	0.034
41	18	-0.466	-0.502	0.036
41	7	-0.462	-0.501	0.038
41	2	-0.465	-0.500	0.034
41	12	-0.461	-0.495	0.034
Max		-0.461	-0.493	0.045
Average		-0.464	-0.499	0.035
Min		-0.469	-0.506	0.027
Std Dev		0.002	0.003	0.004

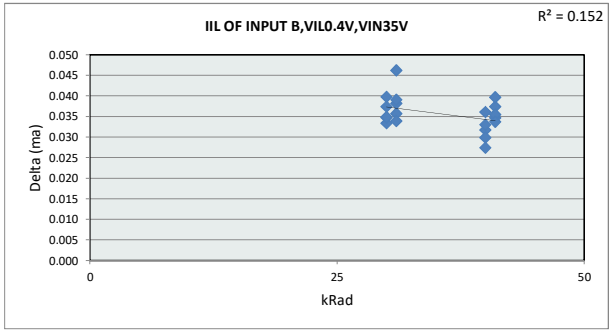


	IIL OF INPUT B,VIL0.4V,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	-0.0001	ma		
Min Limit	-0.905	ma		
kRad	30	31	40	41
LL	-0.905	-0.905	-0.905	-0.905
Min	-0.503	-0.506	-0.499	-0.502
Average	-0.500	-0.502	-0.496	-0.499
Max	-0.497	-0.498	-0.493	-0.495
UL	0.000	0.000	0.000	0.000

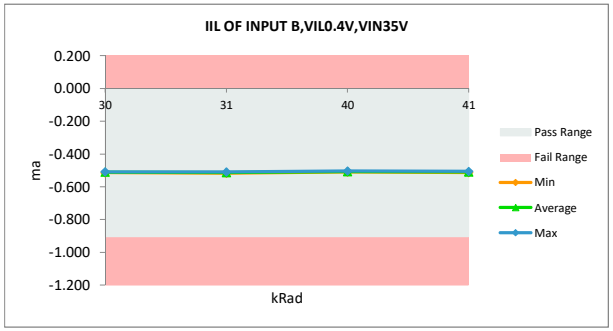


UC1708-SP TID Report

	IIL OF INPUT B,VIL0.4V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ma	ma	
Max Limit	-0.0001	-0.0001	
Min Limit	-0.905	-0.905	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-0.479	-0.512	0.033
30	11	-0.472	-0.510	0.037
30	20	-0.475	-0.509	0.035
30	14	-0.474	-0.514	0.040
30	19	-0.474	-0.508	0.035
40	17	-0.472	-0.503	0.032
40	5	-0.473	-0.509	0.036
40	13	-0.479	-0.508	0.030
40	4	-0.476	-0.503	0.027
40	9	-0.477	-0.510	0.033
31	3	-0.471	-0.518	0.046
31	6	-0.477	-0.512	0.036
31	8	-0.475	-0.514	0.038
31	10	-0.476	-0.510	0.034
31	15	-0.472	-0.512	0.039
41	16	-0.473	-0.508	0.035
41	18	-0.476	-0.513	0.037
41	7	-0.472	-0.512	0.040
41	2	-0.475	-0.511	0.035
41	12	-0.472	-0.506	0.034
	Max	-0.471	-0.503	0.046
	Average	-0.475	-0.510	0.036
	Min	-0.479	-0.518	0.027
	Std Dev	0.002	0.004	0.004

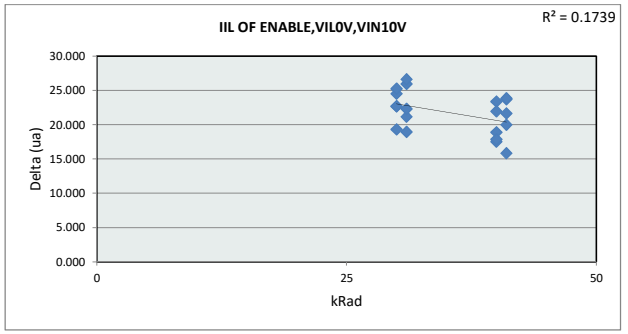


	IIL OF INPUT B,VIL0.4V,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	-0.0001	ma		
Min Limit	-0.905	ma		
kRad	30	31	40	41
LL	-0.905	-0.905	-0.905	-0.905
Min	-0.514	-0.518	-0.510	-0.513
Average	-0.511	-0.513	-0.507	-0.510
Max	-0.508	-0.510	-0.503	-0.506
UL	0.000	0.000	0.000	0.000

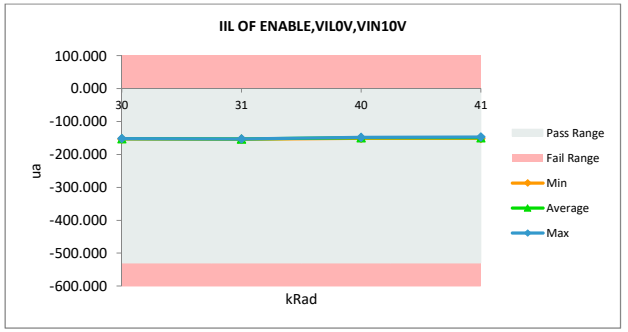


UC1708-SP TID Report

	IIL OF ENABLE,VIL0V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	-0.0001	-0.0001	
Min Limit	-530	-530	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-128.650	-153.166	24.516
30	11	-129.064	-151.736	22.672
30	20	-132.694	-152.000	19.306
30	14	-126.958	-152.188	25.230
30	19	-129.402	-152.094	22.692
40	17	-129.421	-148.312	18.891
40	5	-127.653	-151.021	23.368
40	13	-130.455	-147.973	17.518
40	4	-127.579	-149.515	21.936
40	9	-132.694	-150.550	17.856
31	3	-135.044	-153.993	18.949
31	6	-132.110	-153.260	21.150
31	8	-131.207	-153.505	22.298
31	10	-126.676	-152.602	25.926
31	15	-126.619	-153.241	26.622
41	16	-126.845	-146.807	19.962
41	18	-127.596	-151.284	23.688
41	7	-126.525	-150.362	23.837
41	2	-131.790	-147.616	15.826
41	12	-127.316	-148.951	21.635
	Max	-126.525	-146.807	26.622
	Average	-129.315	-151.009	21.694
	Min	-135.044	-153.993	15.826
	Std Dev	2.528	2.168	2.968

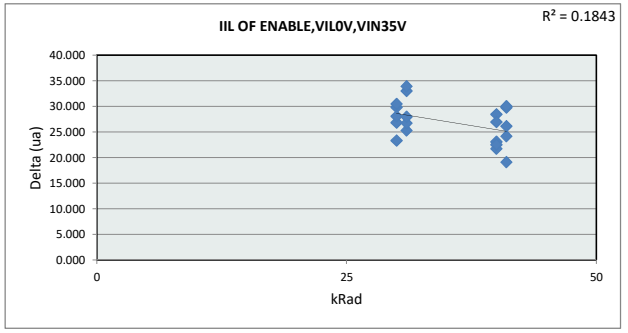


	IIL OF ENABLE,VIL0V,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	-0.0001	ua		
Min Limit	-530	ua		
kRad	30	31	40	41
LL	-530.000	-530.000	-530.000	-530.000
Min	-153.166	-153.993	-151.021	-151.284
Average	-152.237	-153.320	-149.474	-149.004
Max	-151.736	-152.602	-147.973	-146.807
UL	0.000	0.000	0.000	0.000

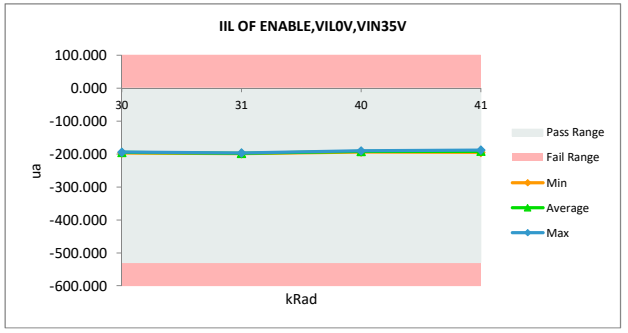


UC1708-SP TID Report

	IIL OF ENABLE,VIL0V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	-0.0001	-0.0001	
Min Limit	-530	-530	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-166.406	-196.260	29.854
30	11	-167.008	-193.852	26.844
30	20	-171.503	-194.831	23.328
30	14	-164.263	-194.755	30.492
30	19	-166.839	-194.925	28.086
40	17	-167.309	-190.392	23.083
40	5	-165.034	-193.495	28.461
40	13	-168.211	-189.959	21.748
40	4	-164.526	-191.483	26.957
40	9	-170.901	-193.439	22.538
31	3	-173.684	-198.988	25.304
31	6	-171.052	-197.784	26.732
31	8	-169.641	-197.615	27.974
31	10	-163.623	-196.636	33.013
31	15	-163.229	-197.163	33.934
41	16	-163.549	-187.739	24.190
41	18	-164.921	-194.699	29.778
41	7	-163.397	-193.439	30.042
41	2	-170.374	-189.489	19.115
41	12	-164.902	-191.031	26.129
	Max	-163.229	-187.739	33.934
	Average	-167.019	-193.899	26.880
	Min	-173.684	-198.988	19.115
	Std Dev	3.192	3.092	3.809

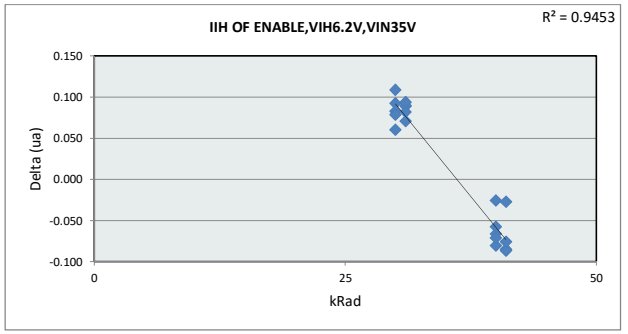


	IIL OF ENABLE,VIL0V,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	-0.0001	ua		
Min Limit	-530	ua		
kRad	30	31	40	41
LL	-530.000	-530.000	-530.000	-530.000
Min	-196.260	-198.988	-193.495	-194.699
Average	-194.925	-197.637	-191.754	-191.279
Max	-193.852	-196.636	-189.959	-187.739
UL	0.000	0.000	0.000	0.000

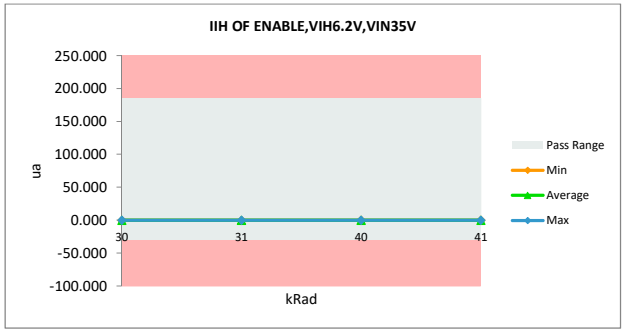


UC1708-SP TID Report

	IIH OF ENABLE,VIH6.2V,VIN35V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	185	185	
Min Limit	-30	-30	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	-0.061	-0.170	0.109
30	11	-0.072	-0.165	0.093
30	20	-0.082	-0.165	0.083
30	14	-0.096	-0.156	0.060
30	19	-0.086	-0.164	0.079
40	17	-0.048	-0.022	-0.025
40	5	-0.086	-0.020	-0.066
40	13	-0.093	-0.036	-0.058
40	4	-0.104	-0.024	-0.080
40	9	-0.111	-0.040	-0.071
31	3	-0.081	-0.170	0.089
31	6	-0.065	-0.154	0.090
31	8	-0.092	-0.174	0.082
31	10	-0.082	-0.153	0.071
31	15	-0.060	-0.154	0.094
41	16	-0.105	-0.020	-0.085
41	18	-0.098	-0.013	-0.086
41	7	-0.111	-0.025	-0.086
41	2	-0.069	-0.041	-0.027
41	12	-0.095	-0.019	-0.076
Max		-0.048	-0.013	0.109
Average		-0.085	-0.094	0.009
Min		-0.111	-0.174	-0.086
Std Dev		0.018	0.071	0.080

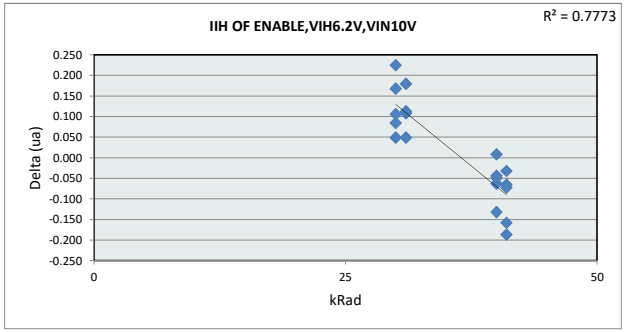


	IIH OF ENABLE,VIH6.2V,VIN35V			
Test Site				
Tester				
Test Number				
Max Limit	185	ua		
Min Limit	-30	ua		
kRad	30	31	40	41
LL	-30.000	-30.000	-30.000	-30.000
Min	-0.170	-0.174	-0.040	-0.042
Average	-0.164	-0.161	-0.029	-0.024
Max	-0.156	-0.153	-0.020	-0.013
UL	185.000	185.000	185.000	185.000

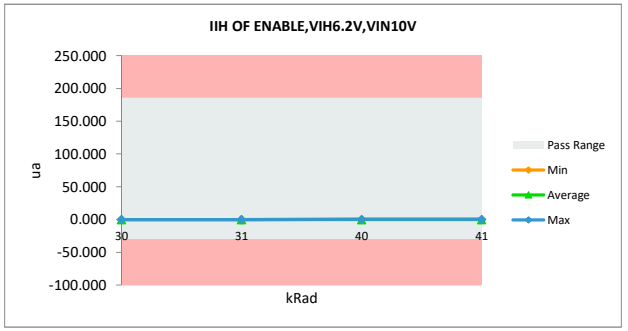


UC1708-SP TID Report

	IIH OF ENABLE,VIH6.2V,VIN10V		
Test Site			
Tester			
Test Number			
Unit	ua	ua	
Max Limit	185	185	
Min Limit	-30	-30	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	0.091	-0.076	0.168
30	11	0.125	0.076	0.049
30	20	0.049	-0.036	0.084
30	14	0.058	-0.048	0.106
30	19	0.160	-0.065	0.225
40	17	0.003	0.047	-0.044
40	5	0.049	0.181	-0.132
40	13	0.134	0.126	0.008
40	4	0.041	0.105	-0.063
40	9	0.032	0.081	-0.049
31	3	0.089	-0.019	0.108
31	6	0.089	0.040	0.049
31	8	0.032	-0.076	0.109
31	10	0.091	-0.022	0.113
31	15	0.049	-0.131	0.180
41	16	-0.056	0.131	-0.187
41	18	0.011	0.076	-0.065
41	7	0.003	0.162	-0.158
41	2	0.010	0.083	-0.073
41	12	0.032	0.064	-0.032
	Max	0.160	0.181	0.225
	Average	0.055	0.035	0.020
	Min	-0.056	-0.131	-0.187
	Std Dev	0.052	0.088	0.117



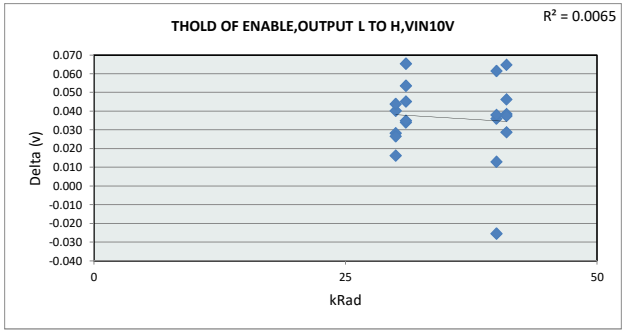
	IIH OF ENABLE,VIH6.2V,VIN10V			
Test Site				
Tester				
Test Number				
Max Limit	185	ua		
Min Limit	-30	ua		
kRad	30	31	40	41
LL	-30.000	-30.000	-30.000	-30.000
Min	-0.076	-0.131	0.047	0.064
Average	-0.030	-0.042	0.108	0.103
Max	0.076	0.040	0.181	0.162
UL	185.000	185.000	185.000	185.000



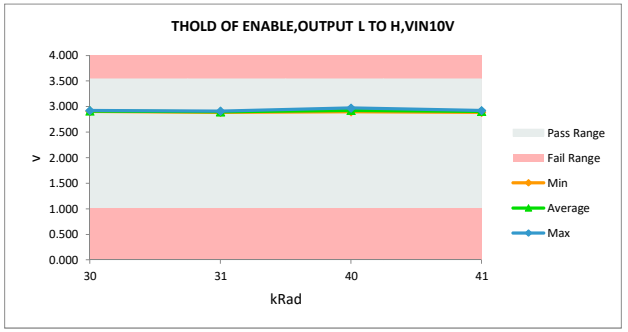
UC1708-SP TID Report

	THOLD OF ENABLE,OUTPUT L TO H,VIN10V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	3.54	3.54
Min Limit	1	1

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	2.937	2.909	0.028
30	11	2.946	2.905	0.040
30	20	2.957	2.913	0.044
30	14	2.937	2.910	0.027
30	19	2.939	2.923	0.016
40	17	2.944	2.908	0.036
40	5	2.946	2.971	-0.026
40	13	2.949	2.911	0.038
40	4	2.950	2.937	0.013
40	9	2.961	2.900	0.062
31	3	2.950	2.896	0.054
31	6	2.946	2.912	0.034
31	8	2.952	2.887	0.065
31	10	2.940	2.905	0.035
31	15	2.947	2.902	0.045
41	16	2.943	2.904	0.039
41	18	2.950	2.922	0.029
41	7	2.954	2.889	0.065
41	2	2.955	2.909	0.046
41	12	2.943	2.906	0.037
Max		2.961	2.971	0.065
Average		2.947	2.911	0.036
Min		2.937	2.887	-0.026
Std Dev		0.007	0.018	0.020



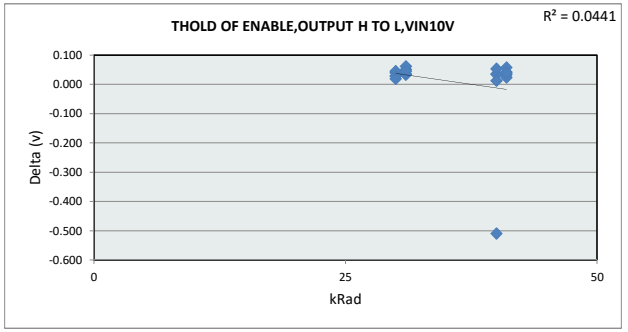
	THOLD OF ENABLE,OUTPUT L TO H			
Test Site				
Tester				
Test Number				
Max Limit	3.54	v		
Min Limit	1	v		
kRad	30	31	40	41
LL	1.000	1.000	1.000	1.000
Min	2.906	2.887	2.900	2.889
Average	2.912	2.900	2.925	2.906
Max	2.923	2.912	2.971	2.922
UL	3.540	3.540	3.540	3.540



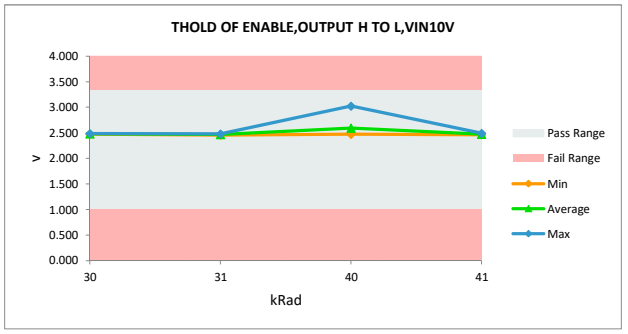
UC1708-SP TID Report

	THOLD OF ENABLE,OUTPUT H TO L,VIN10V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	3.33	3.33
Min Limit	1	1

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	2.503	2.474	0.029
30	11	2.512	2.472	0.040
30	20	2.523	2.477	0.046
30	14	2.504	2.475	0.029
30	19	2.506	2.487	0.019
40	17	2.513	2.477	0.036
40	5	2.513	3.022	-0.509
40	13	2.516	2.481	0.034
40	4	2.514	2.502	0.012
40	9	2.524	2.471	0.053
31	3	2.514	2.463	0.051
31	6	2.511	2.478	0.033
31	8	2.519	2.457	0.062
31	10	2.507	2.471	0.036
31	15	2.512	2.467	0.045
41	16	2.508	2.475	0.033
41	18	2.514	2.490	0.024
41	7	2.520	2.462	0.058
41	2	2.520	2.478	0.042
41	12	2.511	2.474	0.037
	Max	2.524	3.022	0.062
	Average	2.513	2.503	0.011
	Min	2.503	2.457	-0.509
	Std Dev	0.006	0.123	0.123



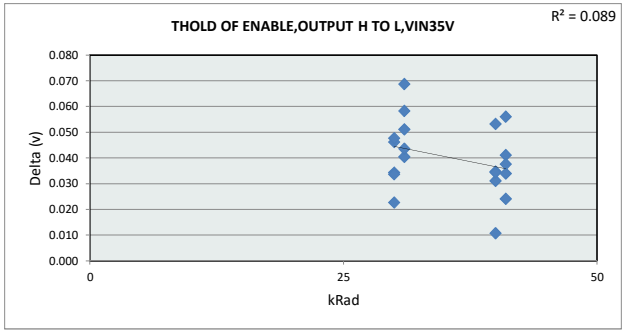
	THOLD OF ENABLE,OUTPUT H TO L			
Test Site				
Tester				
Test Number				
Max Limit	3.33	v		
Min Limit	1	v		
kRad	30	31	40	41
LL	1.000	1.000	1.000	1.000
Min	2.472	2.457	2.471	2.462
Average	2.477	2.467	2.591	2.476
Max	2.487	2.478	3.022	2.490
UL	3.330	3.330	3.330	3.330



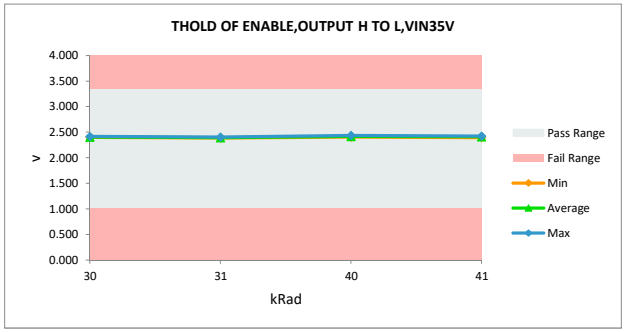
UC1708-SP TID Report

	THOLD OF ENABLE,OUTPUT H TO L,VIN35V	
Test Site		
Tester		
Test Number		
Unit	v	v
Max Limit	3.33	3.33
Min Limit	1	1

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	2.435	2.401	0.034
30	11	2.445	2.399	0.046
30	20	2.453	2.406	0.048
30	14	2.436	2.402	0.034
30	19	2.438	2.415	0.023
40	17	2.445	2.410	0.035
40	5	2.444	2.413	0.031
40	13	2.447	2.413	0.034
40	4	2.446	2.436	0.011
40	9	2.456	2.403	0.053
31	3	2.448	2.389	0.058
31	6	2.443	2.403	0.040
31	8	2.452	2.383	0.069
31	10	2.440	2.397	0.044
31	15	2.446	2.395	0.051
41	16	2.441	2.407	0.034
41	18	2.446	2.422	0.024
41	7	2.450	2.394	0.056
41	2	2.452	2.411	0.041
41	12	2.445	2.407	0.038
Max		2.456	2.436	0.069
Average		2.445	2.405	0.040
Min		2.435	2.383	0.011
Std Dev		0.006	0.012	0.014

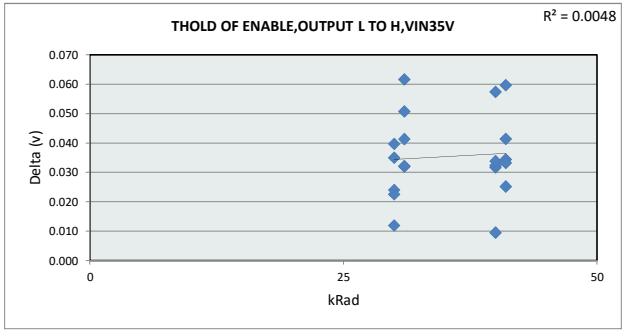


	THOLD OF ENABLE,OUTPUT H TO L			
Test Site				
Tester				
Test Number				
Max Limit	3.33	v		
Min Limit	1	v		
kRad	30	31	40	41
LL	1.000	1.000	1.000	1.000
Min	2.399	2.383	2.403	2.394
Average	2.404	2.393	2.415	2.408
Max	2.415	2.403	2.436	2.422
UL	3.330	3.330	3.330	3.330

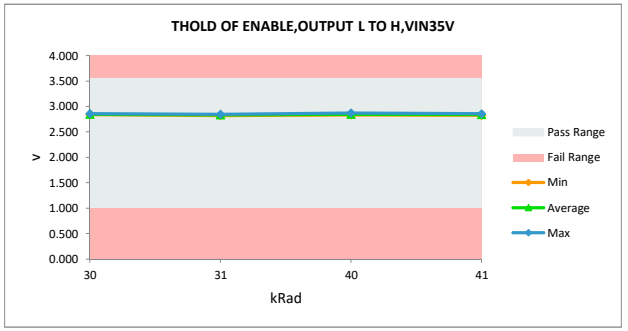


UC1708-SP TID Report

	THOLD OF ENABLE,OUTPUT L TO H,VIN35V		
Test Site			
Tester			
Test Number			
Unit	v	v	
Max Limit	3.54	3.54	
Min Limit	1	1	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	2.869	2.845	0.024
30	11	2.877	2.842	0.035
30	20	2.888	2.849	0.040
30	14	2.869	2.846	0.022
30	19	2.870	2.858	0.012
40	17	2.876	2.844	0.032
40	5	2.877	2.845	0.032
40	13	2.881	2.847	0.034
40	4	2.881	2.872	0.010
40	9	2.893	2.836	0.057
31	3	2.881	2.830	0.051
31	6	2.876	2.845	0.032
31	8	2.884	2.822	0.062
31	10	2.871	2.839	0.032
31	15	2.879	2.838	0.041
41	16	2.874	2.840	0.034
41	18	2.882	2.857	0.025
41	7	2.885	2.826	0.060
41	2	2.886	2.845	0.041
41	12	2.875	2.842	0.033
	Max	2.893	2.872	0.062
	Average	2.879	2.843	0.035
	Min	2.869	2.822	0.010
	Std Dev	0.007	0.011	0.014

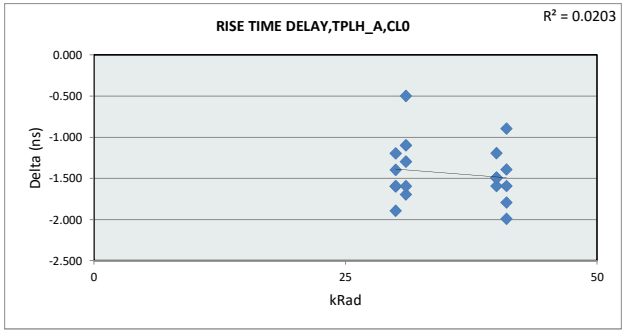


	THOLD OF ENABLE,OUTPUT L TO H			
Test Site				
Tester				
Test Number				
Max Limit	3.54	v		
Min Limit	1	v		
kRad	30	31	40	41
LL	1.000	1.000	1.000	1.000
Min	2.842	2.822	2.836	2.826
Average	2.848	2.835	2.849	2.842
Max	2.858	2.845	2.872	2.857
UL	3.540	3.540	3.540	3.540

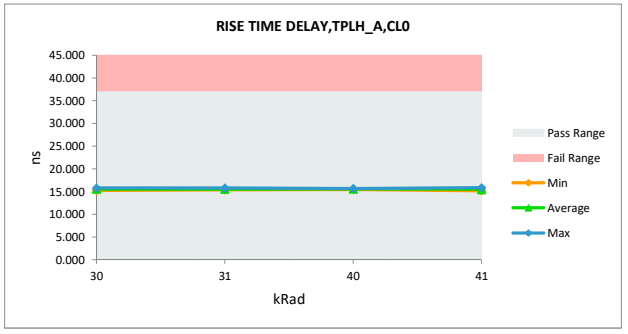


UC1708-SP TID Report

	RISE TIME DELAY,TPLH_A,CL0		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	37	37	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	13.701	15.594	-1.892
30	11	14.199	15.594	-1.394
30	20	14.598	15.792	-1.194
30	14	13.701	15.296	-1.595
30	19	14.000	15.594	-1.594
40	17	14.100	15.692	-1.592
40	5	14.000	15.492	-1.492
40	13	14.199	15.692	-1.492
40	4	14.100	15.592	-1.492
40	9	14.498	15.692	-1.193
31	3	15.096	15.594	-0.498
31	6	14.498	15.792	-1.294
31	8	14.399	15.495	-1.096
31	10	13.901	15.594	-1.693
31	15	13.801	15.395	-1.594
41	16	13.801	15.193	-1.392
41	18	13.801	15.792	-1.991
41	7	13.801	15.392	-1.591
41	2	14.399	15.292	-0.894
41	12	14.100	15.891	-1.792
	Max	15.096	15.891	-0.498
	Average	14.135	15.573	-1.438
	Min	13.701	15.193	-1.991
	Std Dev	0.360	0.187	0.346

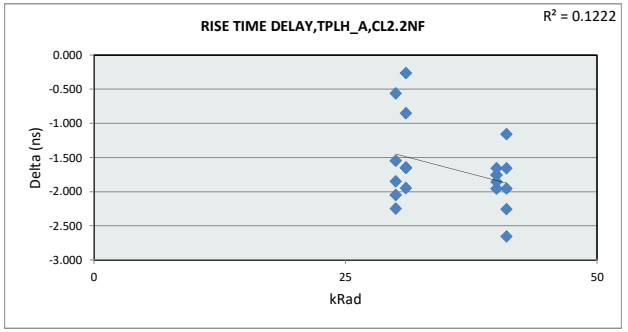


	RISE TIME DELAY,TPLH_A,CL0			
Test Site				
Tester				
Test Number				
Max Limit	37	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	15.296	15.395	15.492	15.193
Average	15.574	15.574	15.632	15.512
Max	15.792	15.792	15.692	15.891
UL	37.000	37.000	37.000	37.000

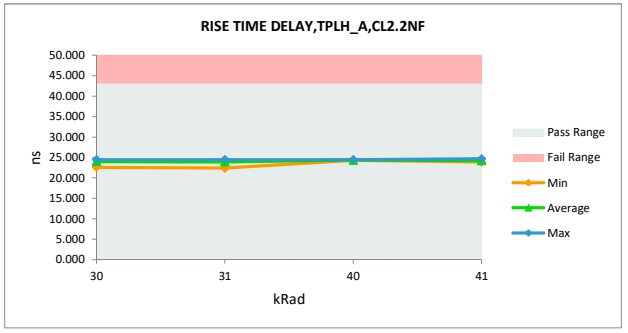


UC1708-SP TID Report

	RISE TIME DELAY,TPLH_A,CL2.2NF		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	43	43	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	22.035	22.594	-0.559
30	11	22.533	24.380	-1.847
30	20	22.932	24.479	-1.547
30	14	21.936	24.181	-2.246
30	19	22.334	24.380	-2.046
40	17	22.733	24.488	-1.756
40	5	22.334	24.289	-1.955
40	13	22.533	24.289	-1.755
40	4	22.434	24.289	-1.855
40	9	22.832	24.488	-1.656
31	3	23.430	24.281	-0.851
31	6	22.832	24.479	-1.647
31	8	22.633	24.281	-1.648
31	10	22.234	24.181	-1.947
31	15	22.135	22.395	-0.260
41	16	22.234	23.889	-1.655
41	18	22.035	24.688	-2.653
41	7	22.234	24.189	-1.955
41	2	22.733	23.889	-1.157
41	12	22.334	24.588	-2.254
	Max	23.430	24.688	-0.260
	Average	22.474	24.136	-1.662
	Min	21.936	22.395	-2.653
	Std Dev	0.368	0.596	0.574



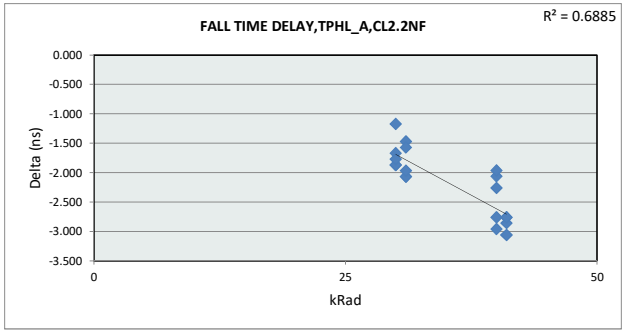
	RISE TIME DELAY,TPLH_A,CL2.2NF			
Test Site				
Tester				
Test Number				
Max Limit	43	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	22.594	22.395	24.289	23.890
Average	24.003	23.923	24.369	24.249
Max	24.479	24.479	24.488	24.688
UL	43.000	43.000	43.000	43.000



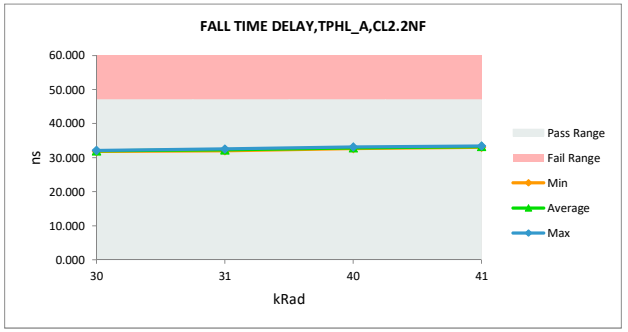
UC1708-SP TID Report

	FALL TIME DELAY,TPHL_A,CL2.2NF	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	47	47
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	29.984	31.854	-1.870
30	11	30.283	32.152	-1.869
30	20	30.781	31.953	-1.172
30	14	30.283	31.953	-1.670
30	19	30.283	32.052	-1.770
40	17	30.482	32.743	-2.261
40	5	30.283	33.042	-2.759
40	13	30.581	32.643	-2.061
40	4	30.183	33.142	-2.959
40	9	30.781	32.743	-1.962
31	3	30.581	32.052	-1.471
31	6	30.581	32.152	-1.570
31	8	30.482	32.549	-2.067
31	10	30.283	32.350	-2.067
31	15	30.382	32.350	-1.968
41	16	30.382	33.441	-3.059
41	18	30.283	33.042	-2.759
41	7	30.183	33.042	-2.859
41	2	30.681	33.441	-2.760
41	12	30.382	33.441	-3.059
Max		30.781	33.441	-1.172
Average		30.407	32.607	-2.200
Min		29.984	31.854	-3.059
Std Dev		0.209	0.541	0.574



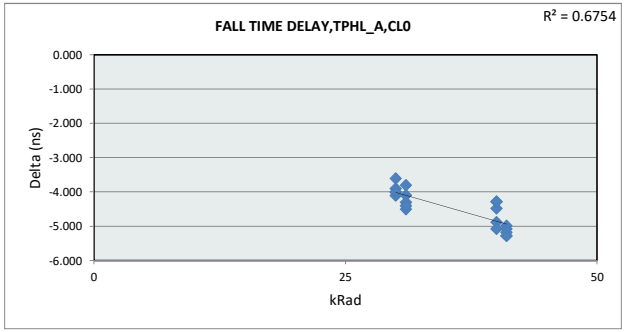
	FALL TIME DELAY,TPHL_A,CL2.2NF			
Test Site				
Tester				
Test Number				
Max Limit	47	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	31.854	32.052	32.643	33.042
Average	31.993	32.291	32.862	33.282
Max	32.152	32.549	33.142	33.441
UL	47.000	47.000	47.000	47.000



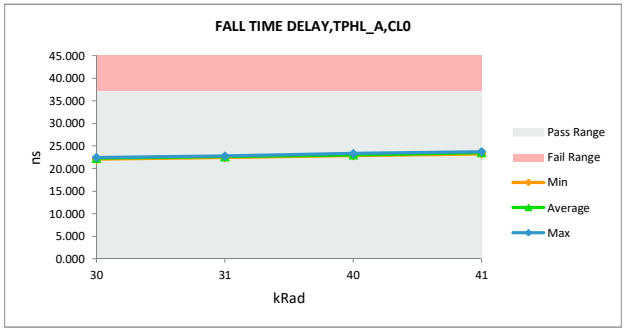
UC1708-SP TID Report

	FALL TIME DELAY,TPHL_A,CL0	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	37	37
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	18.066	22.069	-4.004
30	11	18.365	22.466	-4.102
30	20	18.664	22.268	-3.604
30	14	18.365	22.268	-3.903
30	19	18.265	22.268	-4.003
40	17	18.365	22.847	-4.482
40	5	18.365	23.246	-4.881
40	13	18.564	22.847	-4.283
40	4	18.265	23.346	-5.080
40	9	18.564	22.847	-4.283
31	3	18.664	22.466	-3.803
31	6	18.464	22.566	-4.101
31	8	18.464	22.764	-4.300
31	10	18.166	22.665	-4.499
31	15	18.265	22.665	-4.400
41	16	18.365	23.645	-5.280
41	18	18.265	23.246	-4.981
41	7	18.265	23.346	-5.080
41	2	18.564	23.745	-5.181
41	12	18.365	23.645	-5.280
	Max	18.664	23.745	-3.604
	Average	18.385	22.861	-4.476
	Min	18.066	22.069	-5.280
	Std Dev	0.160	0.510	0.529



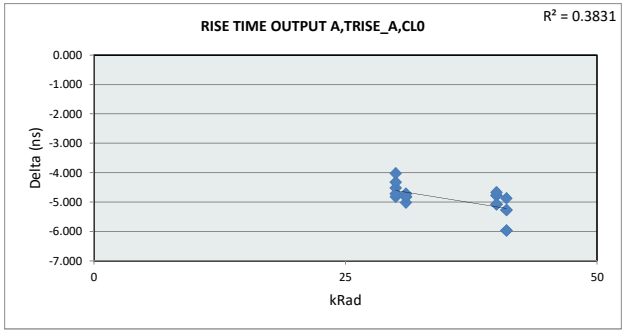
	FALL TIME DELAY,TPHL_A,CL0			
Test Site				
Tester				
Test Number				
Max Limit	37	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	22.070	22.466	22.847	23.246
Average	22.268	22.625	23.026	23.525
Max	22.466	22.764	23.346	23.745
UL	37.000	37.000	37.000	37.000



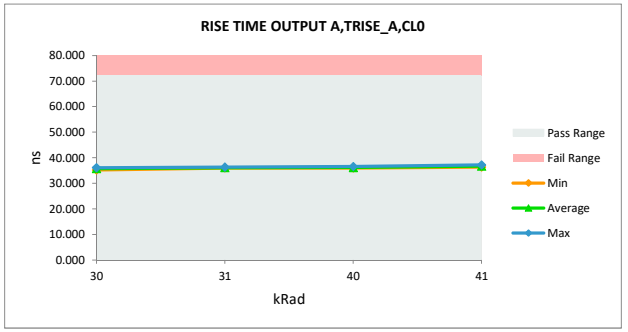
UC1708-SP TID Report

	RISE TIME OUTPUT A,TRISE_A,CL0	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	72	72
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	30.784	35.605	-4.821
30	11	31.282	35.803	-4.521
30	20	31.581	35.902	-4.321
30	14	31.182	35.208	-4.025
30	19	31.382	36.101	-4.719
40	17	31.282	36.355	-5.073
40	5	31.282	36.055	-4.773
40	13	31.282	36.055	-4.773
40	4	31.282	35.956	-4.674
40	9	31.481	36.554	-5.073
31	3	31.182	36.001	-4.819
31	6	31.282	36.001	-4.719
31	8	31.282	36.299	-5.017
31	10	31.282	36.101	-4.819
31	15	31.282	36.101	-4.819
41	16	31.182	36.455	-5.272
41	18	31.182	37.153	-5.971
41	7	31.083	36.355	-5.272
41	2	31.581	36.455	-4.874
41	12	31.182	37.153	-5.971
	Max	31.581	37.153	-4.025
	Average	31.267	36.183	-4.916
	Min	30.784	35.208	-5.971
	Std Dev	0.172	0.454	0.462

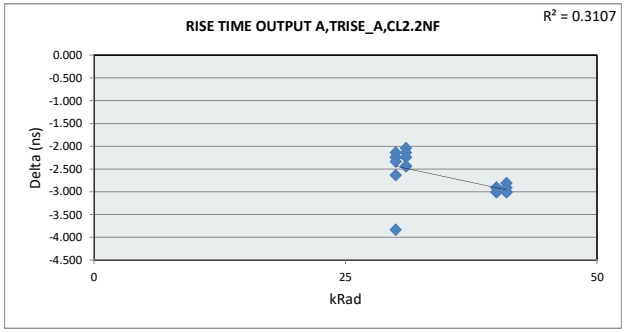


	RISE TIME OUTPUT A,TRISE_A,CL0			
Test Site				
Tester				
Test Number				
Max Limit	72	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	35.208	36.002	35.956	36.355
Average	35.724	36.101	36.195	36.714
Max	36.101	36.299	36.554	37.153
UL	72.000	72.000	72.000	72.000

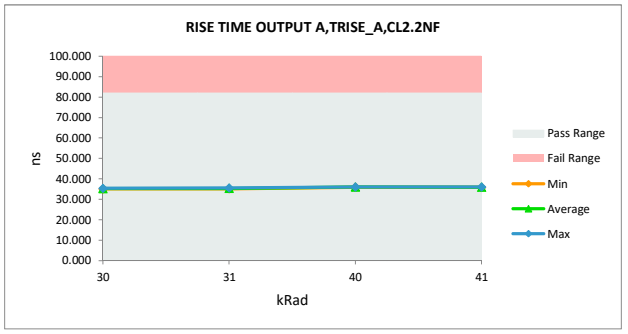


UC1708-SP TID Report

	RISE TIME OUTPUT A,TRISE_A,CL2.2NF		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	82	82	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	32.610	35.247	-2.637
30	11	31.514	35.346	-3.832
30	20	33.009	35.247	-2.239
30	14	32.909	35.247	-2.338
30	19	32.909	35.049	-2.140
40	17	33.108	36.018	-2.909
40	5	32.909	35.918	-3.009
40	13	33.108	36.018	-2.909
40	4	33.009	36.018	-3.009
40	9	33.108	36.018	-2.909
31	3	33.108	35.148	-2.040
31	6	33.108	35.247	-2.139
31	8	33.108	35.545	-2.437
31	10	32.909	35.148	-2.239
31	15	33.108	35.545	-2.437
41	16	33.009	36.018	-3.009
41	18	32.909	35.918	-3.009
41	7	32.909	35.818	-2.909
41	2	33.208	36.018	-2.810
41	12	33.009	36.018	-3.009
	Max	33.208	36.018	-2.040
	Average	32.929	35.627	-2.698
	Min	31.514	35.049	-3.832
	Std Dev	0.358	0.380	0.442

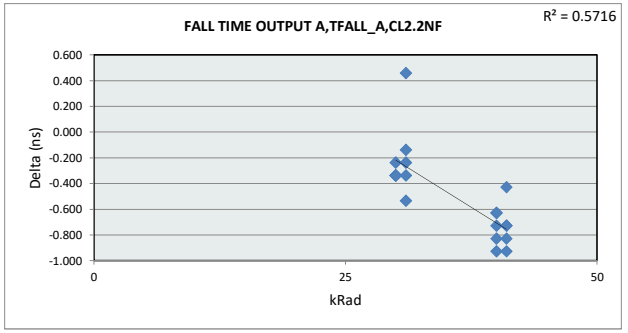


	RISE TIME OUTPUT A,TRISE_A,CL2			
Test Site				
Tester				
Test Number				
Max Limit	82	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	35.049	35.148	35.918	35.818
Average	35.227	35.327	35.998	35.958
Max	35.346	35.545	36.018	36.018
UL	82.000	82.000	82.000	82.000

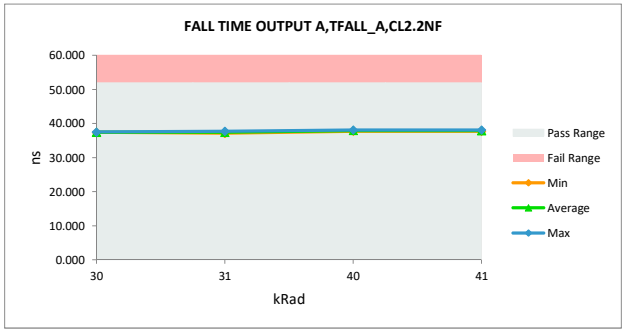


UC1708-SP TID Report

	FALL TIME OUTPUT A,TFALL_A,CL2.2NF		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	52	52	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	37.085	37.421	-0.336
30	11	37.185	37.521	-0.335
30	20	37.285	37.521	-0.236
30	14	37.085	37.421	-0.336
30	19	37.085	37.421	-0.336
40	17	37.185	37.812	-0.627
40	5	37.185	38.112	-0.927
40	13	37.085	37.712	-0.627
40	4	37.285	38.112	-0.827
40	9	37.185	37.912	-0.727
31	3	37.584	37.124	0.460
31	6	37.185	37.322	-0.137
31	8	37.185	37.521	-0.335
31	10	37.085	37.322	-0.237
31	15	37.185	37.719	-0.534
41	16	37.185	38.112	-0.927
41	18	36.986	37.712	-0.727
41	7	37.285	37.712	-0.428
41	2	37.285	38.012	-0.727
41	12	37.185	38.012	-0.827
	Max	37.584	38.112	0.460
	Average	37.190	37.677	-0.487
	Min	36.986	37.124	-0.927
	Std Dev	0.123	0.299	0.332



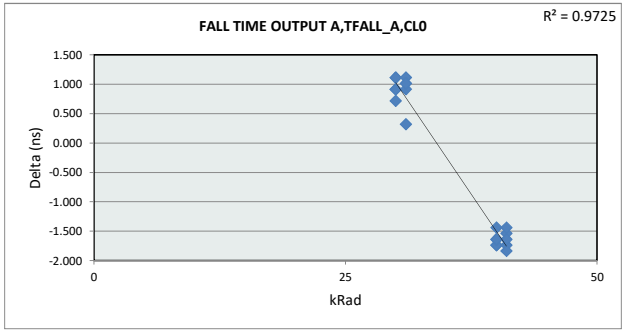
	FALL TIME OUTPUT A,TFALL_A,CL2			
Test Site				
Tester				
Test Number				
Max Limit	52	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	37.421	37.124	37.712	37.712
Average	37.461	37.402	37.932	37.912
Max	37.521	37.719	38.112	38.112
UL	52.000	52.000	52.000	52.000



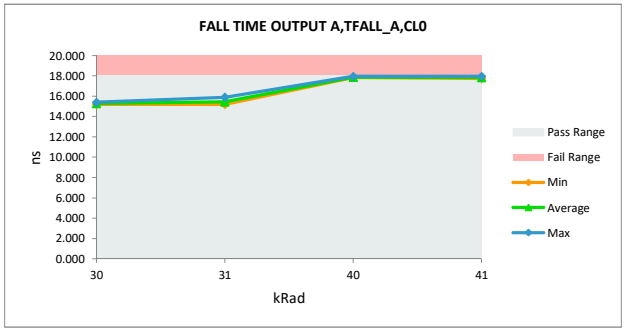
UC1708-SP TID Report

	FALL TIME OUTPUT A,TFALL_A,CL0	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	18	18
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	16.213	15.300	0.913
30	11	16.313	15.201	1.112
30	20	16.412	15.300	1.112
30	14	16.113	15.201	0.913
30	19	16.113	15.399	0.714
40	17	16.213	17.950	-1.737
40	5	16.113	17.850	-1.737
40	13	16.213	17.850	-1.638
40	4	16.213	17.850	-1.638
40	9	16.412	17.850	-1.438
31	3	16.512	15.399	1.113
31	6	16.313	15.399	0.913
31	8	16.313	15.300	1.013
31	10	16.213	15.201	1.012
31	15	16.213	15.895	0.318
41	16	16.213	17.950	-1.737
41	18	16.014	17.850	-1.837
41	7	16.213	17.751	-1.538
41	2	16.313	17.950	-1.638
41	12	16.313	17.751	-1.438
Max		16.512	17.950	1.113
Average		16.248	16.610	-0.362
Min		16.014	15.201	-1.837
Std Dev		0.118	1.292	1.322

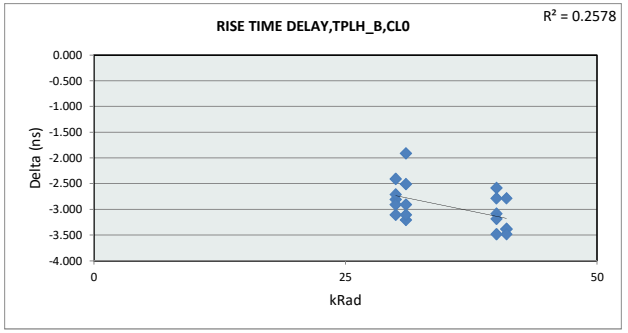


	FALL TIME OUTPUT A,TFALL_A,CL0			
Test Site				
Tester				
Test Number				
Max Limit	18	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	15.201	15.201	17.850	17.751
Average	15.280	15.439	17.870	17.850
Max	15.399	15.895	17.950	17.950
UL	18.000	18.000	18.000	18.000

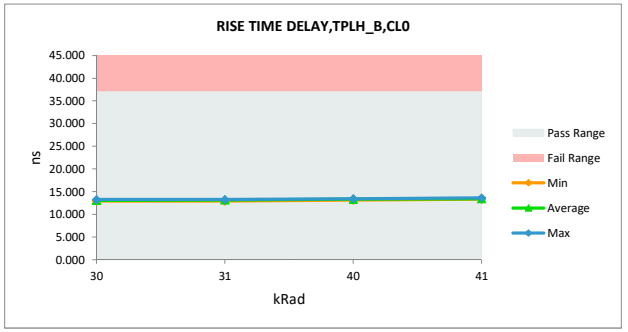


UC1708-SP TID Report

	RISE TIME DELAY,TPLH_B,CL0		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	37	37	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	10.165	12.974	-2.809
30	11	10.365	13.073	-2.709
30	20	10.863	13.272	-2.409
30	14	9.966	13.073	-3.107
30	19	10.265	13.173	-2.908
40	17	10.365	13.448	-3.083
40	5	10.265	13.448	-3.183
40	13	10.464	13.248	-2.784
40	4	9.966	13.448	-3.482
40	9	10.564	13.149	-2.585
31	3	11.062	12.974	-1.912
31	6	10.664	13.173	-2.509
31	8	10.365	13.272	-2.907
31	10	10.066	13.272	-3.206
31	15	10.165	13.272	-3.106
41	16	10.066	13.448	-3.382
41	18	10.066	13.448	-3.382
41	7	10.066	13.448	-3.382
41	2	10.564	13.348	-2.784
41	12	10.165	13.648	-3.482
	Max	11.062	13.648	-1.912
	Average	10.325	13.281	-2.956
	Min	9.966	12.974	-3.482
	Std Dev	0.299	0.181	0.407

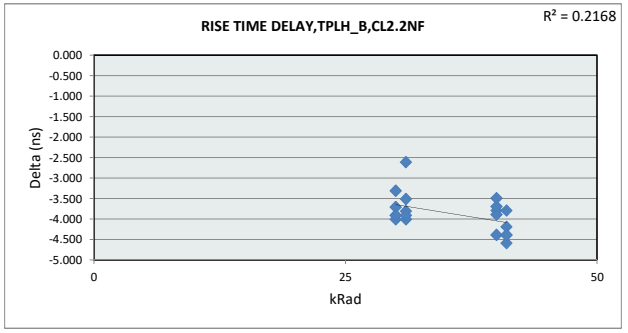


	RISE TIME DELAY,TPLH_B,CL0			
Test Site				
Tester				
Test Number				
Max Limit	37	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	12.974	12.974	13.149	13.348
Average	13.113	13.192	13.348	13.468
Max	13.272	13.272	13.448	13.648
UL	37.000	37.000	37.000	37.000

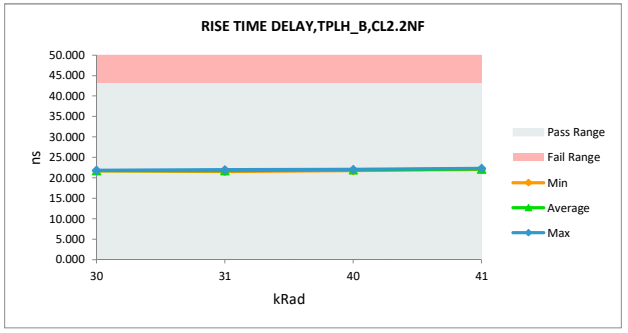


UC1708-SP TID Report

	RISE TIME DELAY,TPLH_B,CL2.2NF		
Test Site			
Tester			
Test Number			
Unit	ns	ns	
Max Limit	43	43	
Min Limit	0	0	
kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	17.757	21.664	-3.907
30	11	18.056	21.763	-3.707
30	20	18.554	21.862	-3.308
30	14	17.658	21.664	-4.007
30	19	17.956	21.862	-3.906
40	17	18.255	22.046	-3.791
40	5	18.156	22.046	-3.890
40	13	18.156	21.846	-3.691
40	4	17.658	22.046	-4.388
40	9	18.255	21.747	-3.491
31	3	18.953	21.565	-2.612
31	6	18.255	21.763	-3.508
31	8	18.156	21.962	-3.806
31	10	17.757	21.763	-4.006
31	15	17.857	21.763	-3.906
41	16	17.757	22.146	-4.388
41	18	17.558	22.146	-4.588
41	7	17.857	22.046	-4.189
41	2	18.255	22.046	-3.791
41	12	17.956	22.345	-4.389
Max		18.953	22.345	-2.612
Average		18.041	21.905	-3.863
Min		17.558	21.565	-4.588
Std Dev		0.338	0.200	0.442



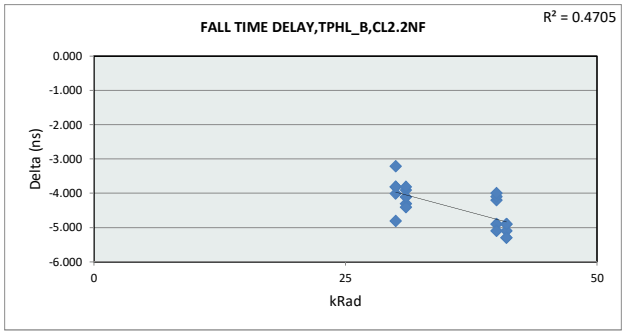
	RISE TIME DELAY,TPLH_B,CL2.2NF			
Test Site				
Tester				
Test Number				
Max Limit	43	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	21.664	21.565	21.747	22.046
Average	21.763	21.763	21.946	22.146
Max	21.863	21.962	22.046	22.345
UL	43.000	43.000	43.000	43.000



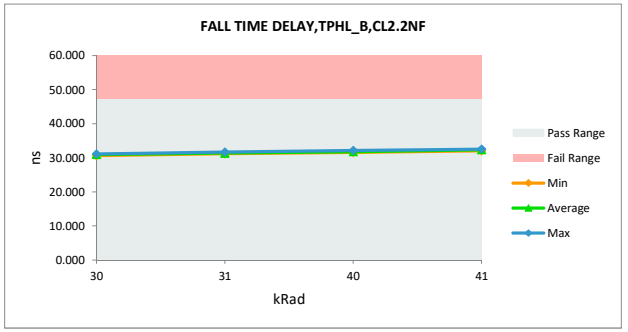
UC1708-SP TID Report

	FALL TIME DELAY,TPHL_B,CL2.2NF	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	47	47
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	25.851	30.659	-4.809
30	11	27.245	31.056	-3.811
30	20	27.743	30.957	-3.214
30	14	27.046	31.056	-4.010
30	19	27.146	30.957	-3.811
40	17	27.444	31.644	-4.199
40	5	27.046	31.943	-4.897
40	13	27.444	31.544	-4.099
40	4	27.046	32.143	-5.097
40	9	27.544	31.544	-4.000
31	3	27.245	31.156	-3.910
31	6	27.345	31.156	-3.811
31	8	27.345	31.652	-4.307
31	10	27.046	31.453	-4.407
31	15	27.245	31.354	-4.109
41	16	27.245	32.542	-5.297
41	18	27.146	32.043	-4.897
41	7	27.046	32.143	-5.097
41	2	27.544	32.442	-4.898
41	12	27.245	32.542	-5.297
Max		27.743	32.542	-3.214
Average		27.200	31.599	-4.399
Min		25.851	30.659	-5.297
Std Dev		0.373	0.570	0.594



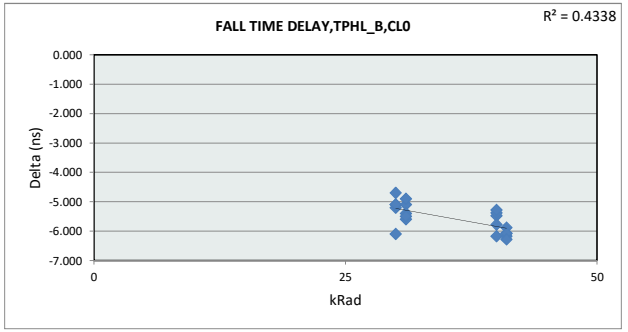
	FALL TIME DELAY,TPHL_B,CL2.2NF			
Test Site				
Tester				
Test Number				
Max Limit	47	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	30.659	31.156	31.544	32.043
Average	30.937	31.354	31.764	32.342
Max	31.056	31.652	32.143	32.542
UL	47.000	47.000	47.000	47.000



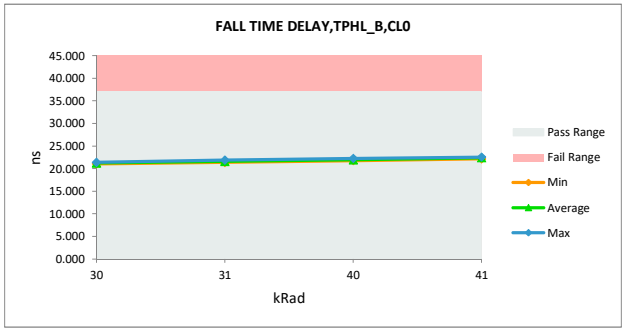
UC1708-SP TID Report

	FALL TIME DELAY,TPHL_B,CL0	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	37	37
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	14.974	21.069	-6.095
30	11	16.170	21.367	-5.197
30	20	16.569	21.268	-4.699
30	14	16.170	21.268	-5.098
30	19	16.170	21.268	-5.098
40	17	16.369	21.847	-5.477
40	5	16.170	21.946	-5.776
40	13	16.369	21.747	-5.378
40	4	16.070	22.246	-6.175
40	9	16.569	21.847	-5.278
31	3	16.270	21.367	-5.098
31	6	16.469	21.367	-4.898
31	8	16.469	21.863	-5.394
31	10	16.070	21.665	-5.594
31	15	16.170	21.665	-5.495
41	16	16.369	22.545	-6.176
41	18	16.070	22.146	-6.076
41	7	16.270	22.146	-5.876
41	2	16.469	22.545	-6.076
41	12	16.270	22.545	-6.276
	Max	16.569	22.545	-4.699
	Average	16.225	21.786	-5.562
	Min	14.974	21.069	-6.276
	Std Dev	0.335	0.465	0.478



	FALL TIME DELAY,TPHL_B,CL0			
Test Site				
Tester				
Test Number				
Max Limit	37	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	21.070	21.367	21.747	22.146
Average	21.248	21.585	21.926	22.385
Max	21.367	21.863	22.246	22.545
UL	37.000	37.000	37.000	37.000

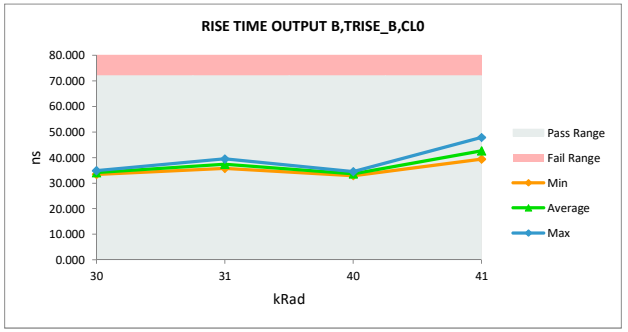


UC1708-SP TID Report

	RISE TIME OUTPUT B,TRISE_B,CL0	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	72	72
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	42.649	33.445	9.203
30	11	41.354	34.537	6.817
30	20	42.350	34.934	7.416
30	14	41.354	33.941	7.412
30	19	41.354	33.743	7.611
40	17	41.254	33.243	8.011
40	5	41.652	33.941	7.711
40	13	41.852	33.642	8.210
40	4	40.756	34.540	6.216
40	9	41.752	32.943	8.809
31	3	43.446	35.827	7.619
31	6	41.852	39.498	2.354
31	8	41.553	38.406	3.146
31	10	41.553	37.017	4.535
31	15	41.553	36.223	5.329
41	16	40.955	39.431	1.524
41	18	40.258	45.021	-4.763
41	7	41.652	41.128	0.524
41	2	41.652	39.631	2.022
41	12	41.154	47.915	-6.761
Max		43.446	47.915	9.203
Average		41.598	36.950	4.647
Min		40.258	32.943	-6.761
Std Dev		0.675	4.128	4.424

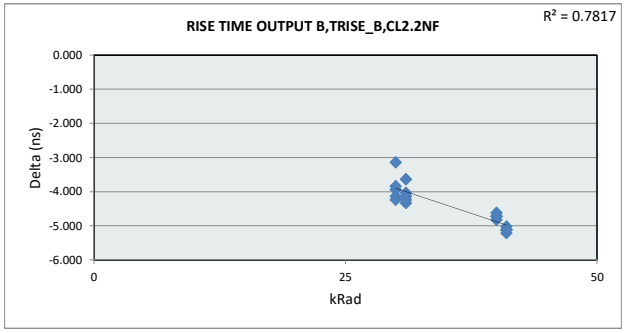
	RISE TIME OUTPUT B,TRISE_B,CL0			
Test Site				
Tester				
Test Number				
Max Limit	72	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	33.445	35.827	32.943	39.431
Average	34.120	37.394	33.662	42.625
Max	34.934	39.498	34.540	47.915
UL	72.000	72.000	72.000	72.000



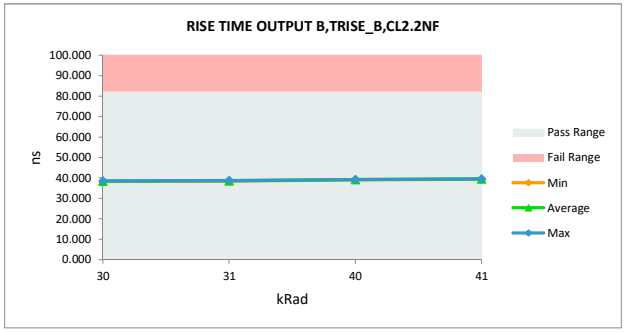
UC1708-SP TID Report

	RISE TIME OUTPUT B,TRISE_B,CL2.2NF	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	82	82
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	35.095	38.233	-3.138
30	11	34.497	38.431	-3.934
30	20	34.597	38.431	-3.835
30	14	34.298	38.431	-4.134
30	19	34.298	38.531	-4.233
40	17	34.497	39.114	-4.617
40	5	34.397	39.214	-4.817
40	13	34.497	39.214	-4.717
40	4	34.397	39.114	-4.717
40	9	34.397	39.114	-4.717
31	3	34.796	38.431	-3.636
31	6	34.497	38.531	-4.034
31	8	34.397	38.729	-4.332
31	10	34.397	38.531	-4.133
31	15	34.497	38.729	-4.232
41	16	34.397	39.513	-5.116
41	18	34.198	39.314	-5.116
41	7	34.397	39.414	-5.016
41	2	34.298	39.513	-5.216
41	12	34.397	39.513	-5.116
	Max	35.095	39.513	-3.138
	Average	34.462	38.902	-4.440
	Min	34.198	38.233	-5.216
	Std Dev	0.195	0.441	0.568



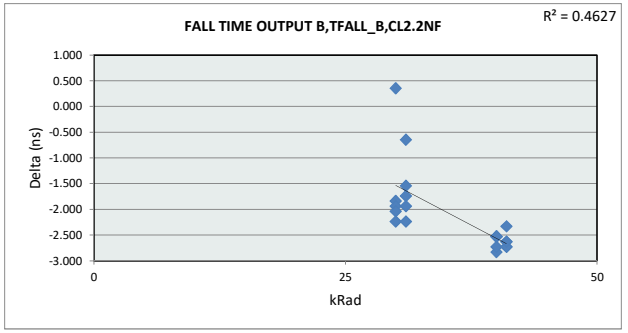
	RISE TIME OUTPUT B,TRISE_B,CL2			
Test Site				
Tester				
Test Number				
Max Limit	82	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	38.233	38.432	39.114	39.314
Average	38.412	38.590	39.154	39.453
Max	38.531	38.729	39.214	39.513
UL	82.000	82.000	82.000	82.000



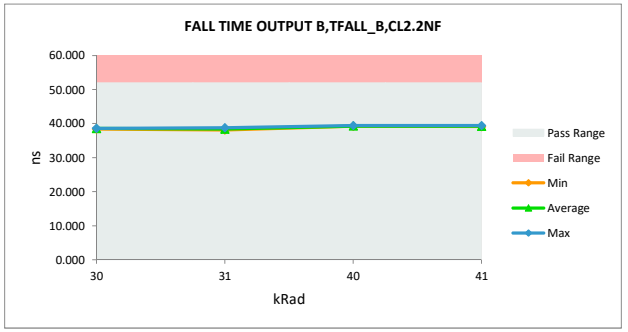
UC1708-SP TID Report

	FALL TIME OUTPUT B,TFALL_B,CL2.2NF	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	52	52
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	38.775	38.422	0.352
30	11	36.782	38.621	-1.839
30	20	36.682	38.621	-1.938
30	14	36.483	38.521	-2.038
30	19	36.384	38.621	-2.237
40	17	36.682	39.212	-2.529
40	5	36.583	39.411	-2.828
40	13	36.583	39.312	-2.729
40	4	36.782	39.312	-2.529
40	9	36.682	39.212	-2.529
31	3	37.479	38.125	-0.645
31	6	36.782	38.323	-1.541
31	8	36.583	38.521	-1.939
31	10	36.583	38.323	-1.740
31	15	36.583	38.819	-2.236
41	16	36.583	39.212	-2.629
41	18	36.384	39.112	-2.728
41	7	36.782	39.112	-2.330
41	2	36.682	39.411	-2.729
41	12	36.782	39.411	-2.629
Max		38.775	39.411	0.352
Average		36.782	38.882	-2.100
Min		36.384	38.125	-2.828
Std Dev		0.520	0.430	0.782



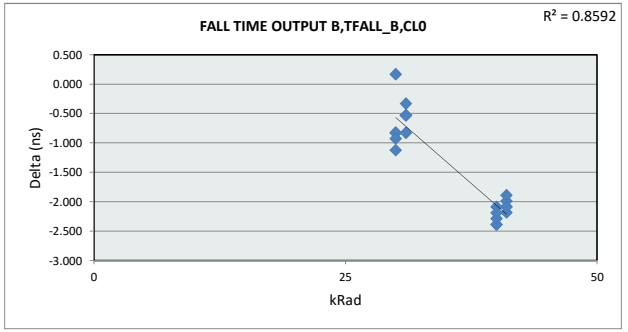
	FALL TIME OUTPUT B,TFALL_B,CL2			
Test Site				
Tester				
Test Number				
Max Limit	52	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	38.422	38.125	39.212	39.112
Average	38.561	38.422	39.292	39.252
Max	38.621	38.819	39.411	39.411
UL	52.000	52.000	52.000	52.000



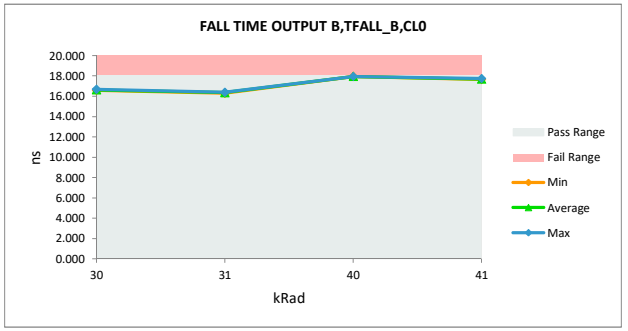
UC1708-SP TID Report

	FALL TIME OUTPUT B,TFALL_B,CL0	
Test Site		
Tester		
Test Number		
Unit	ns	ns
Max Limit	18	18
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	16.859	16.689	0.170
30	11	15.763	16.590	-0.826
30	20	15.763	16.590	-0.826
30	14	15.564	16.689	-1.125
30	19	15.664	16.590	-0.926
40	17	15.564	17.950	-2.386
40	5	15.564	17.950	-2.386
40	13	15.664	17.950	-2.287
40	4	15.863	17.950	-2.087
40	9	15.763	17.950	-2.187
31	3	16.062	16.391	-0.329
31	6	15.863	16.391	-0.528
31	8	15.763	16.292	-0.529
31	10	15.763	16.292	-0.529
31	15	15.564	16.391	-0.827
41	16	15.464	17.651	-2.186
41	18	15.564	17.651	-2.087
41	7	15.763	17.751	-1.987
41	2	15.763	17.651	-1.887
41	12	15.664	17.751	-2.087
Max		16.859	17.950	0.170
Average		15.763	17.155	-1.392
Min		15.464	16.292	-2.386
Std Dev		0.293	0.697	0.832



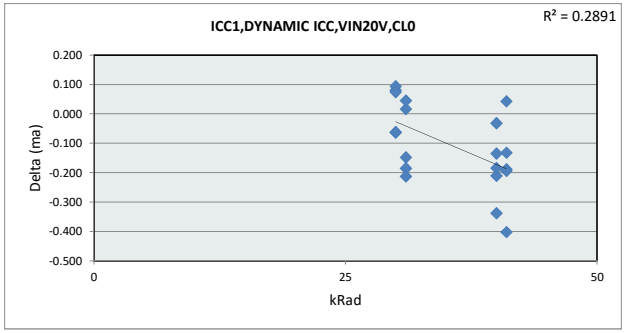
	FALL TIME OUTPUT B,TFALL_B,CL0			
Test Site				
Tester				
Test Number				
Max Limit	18	ns		
Min Limit	0	ns		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	16.590	16.292	17.950	17.651
Average	16.629	16.352	17.950	17.691
Max	16.689	16.391	17.950	17.751
UL	18.000	18.000	18.000	18.000



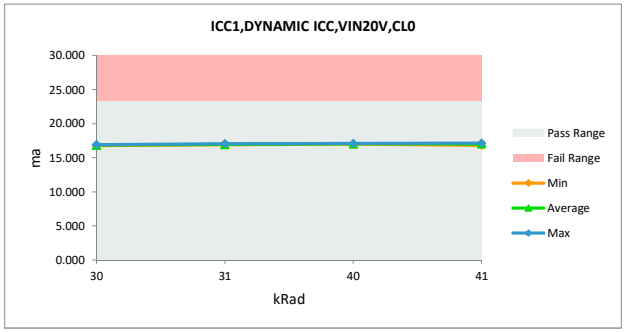
UC1708-SP TID Report

	ICC1,DYNAMIC ICC,VIN20V,CL0	
Test Site		
Tester		
Test Number		
Unit	ma	ma
Max Limit	23.2	23.2
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	16.865	16.929	-0.064
30	11	16.867	16.787	0.080
30	20	16.894	16.800	0.094
30	14	16.840	16.902	-0.062
30	19	16.917	16.844	0.074
40	17	16.835	17.046	-0.211
40	5	16.859	17.044	-0.185
40	13	16.977	17.009	-0.032
40	4	16.731	17.069	-0.339
40	9	16.944	17.079	-0.135
31	3	16.873	17.059	-0.185
31	6	16.948	16.931	0.017
31	8	16.992	16.947	0.045
31	10	16.780	16.928	-0.148
31	15	16.735	16.948	-0.213
41	16	16.795	16.984	-0.188
41	18	16.921	17.116	-0.194
41	7	16.746	17.148	-0.402
41	2	16.927	17.059	-0.133
41	12	16.852	16.809	0.042
	Max	16.992	17.148	0.094
	Average	16.865	16.972	-0.107
	Min	16.731	16.787	-0.402
	Std Dev	0.078	0.107	0.140



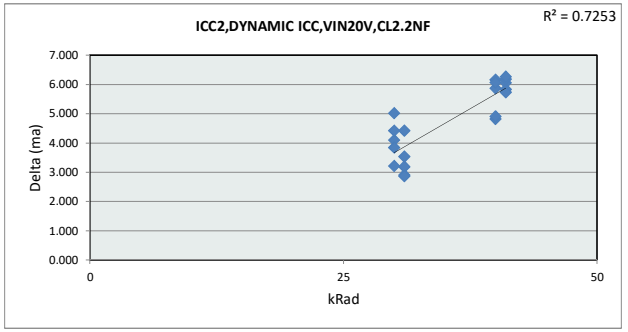
	ICC1,DYNAMIC ICC,VIN20V,CL0			
Test Site				
Tester				
Test Number				
Max Limit	23.2	ma		
Min Limit	0	ma		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	16.787	16.929	17.009	16.809
Average	16.852	16.963	17.049	17.023
Max	16.929	17.059	17.079	17.148
UL	23.200	23.200	23.200	23.200



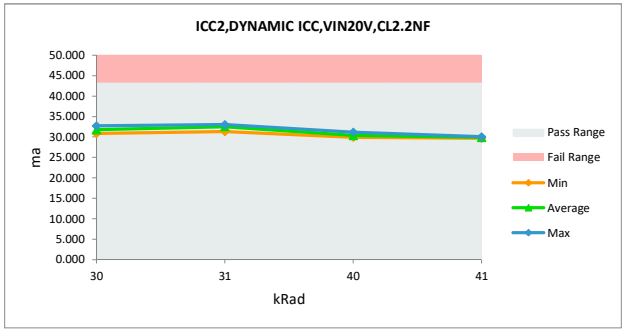
UC1708-SP TID Report

	ICC2,DYNAMIC ICC,VIN20V,CL2.2NF	
Test Site		
Tester		
Test Number		
Unit	ma	ma
Max Limit	43.2	43.2
Min Limit	0	0

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	35.946	31.843	4.103
30	11	35.900	30.882	5.019
30	20	35.779	31.360	4.420
30	14	35.946	32.732	3.214
30	19	35.891	32.049	3.842
40	17	35.828	29.959	5.869
40	5	35.998	31.178	4.820
40	13	36.115	29.955	6.160
40	4	35.596	30.691	4.905
40	9	36.057	29.990	6.067
31	3	35.821	32.917	2.903
31	6	36.027	32.839	3.188
31	8	36.096	32.563	3.534
31	10	35.746	31.328	4.419
31	15	35.883	33.017	2.866
41	16	35.908	29.853	6.055
41	18	35.834	30.000	5.834
41	7	35.785	30.050	5.735
41	2	36.110	29.928	6.182
41	12	35.974	29.709	6.265
	Max	36.115	33.017	6.265
	Average	35.912	31.142	4.770
	Min	35.596	29.709	2.866
	Std Dev	0.135	1.205	1.213



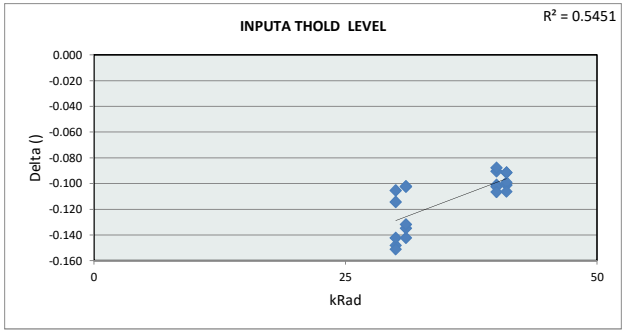
	ICC2,DYNAMIC ICC,VIN20V,CL2.2			
Test Site				
Tester				
Test Number				
Max Limit	43.2	ma		
Min Limit	0	ma		
kRad	30	31	40	41
LL	0.000	0.000	0.000	0.000
Min	30.882	31.328	29.955	29.709
Average	31.773	32.533	30.355	29.908
Max	32.732	33.017	31.178	30.050
UL	43.200	43.200	43.200	43.200



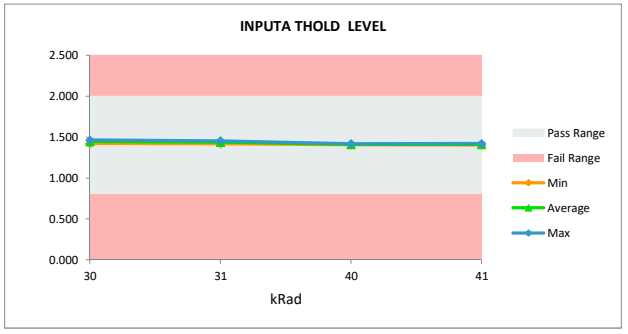
UC1708-SP TID Report

	INPUTA THOLD LEVEL	
Test Site		
Tester		
Test Number		
Unit		
Max Limit	2	2
Min Limit	0.8	0.8

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.326	1.441	-0.114
30	11	1.317	1.422	-0.105
30	20	1.312	1.460	-0.148
30	14	1.314	1.465	-0.151
30	19	1.312	1.454	-0.142
40	17	1.317	1.407	-0.090
40	5	1.313	1.414	-0.101
40	13	1.311	1.414	-0.102
40	4	1.320	1.408	-0.088
40	9	1.313	1.419	-0.106
31	3	1.320	1.422	-0.102
31	6	1.314	1.456	-0.142
31	8	1.313	1.448	-0.135
31	10	1.316	1.419	-0.102
31	15	1.319	1.451	-0.132
41	16	1.316	1.408	-0.092
41	18	1.316	1.417	-0.101
41	7	1.316	1.416	-0.099
41	2	1.312	1.403	-0.091
41	12	1.316	1.422	-0.106
Max		1.326	1.465	-0.088
Average		1.316	1.428	-0.113
Min		1.311	1.403	-0.151
Std Dev		0.004	0.020	0.021



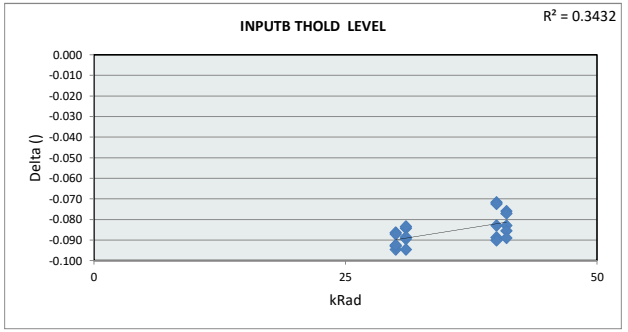
	INPUTA THOLD LEVEL			
Test Site				
Tester				
Test Number				
Max Limit	2			
Min Limit	0.8			
kRad	30	31	40	41
LL	0.800	0.800	0.800	0.800
Min	1.422	1.419	1.407	1.403
Average	1.448	1.439	1.412	1.413
Max	1.465	1.456	1.419	1.422
UL	2.000	2.000	2.000	2.000



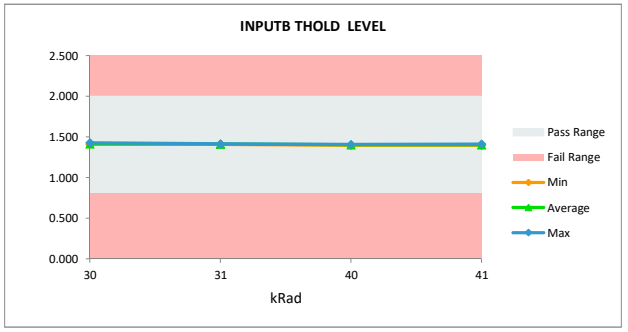
UC1708-SP TID Report

	INPUTB THOLD LEVEL	
Test Site		
Tester		
Test Number		
Unit		
Max Limit	2	2
Min Limit	0.8	0.8

kRad	Serial #	Pre_30k&40kRad_LDR_UnBiased	Post_30k&40kRad_LDR_Unbiased	Delta
30	1	1.333	1.428	-0.095
30	11	1.324	1.410	-0.086
30	20	1.319	1.412	-0.093
30	14	1.321	1.408	-0.087
30	19	1.319	1.412	-0.092
40	17	1.324	1.396	-0.072
40	5	1.319	1.408	-0.089
40	13	1.319	1.402	-0.083
40	4	1.326	1.398	-0.073
40	9	1.318	1.408	-0.090
31	3	1.326	1.411	-0.084
31	6	1.321	1.410	-0.090
31	8	1.317	1.412	-0.095
31	10	1.324	1.408	-0.083
31	15	1.326	1.415	-0.089
41	16	1.322	1.398	-0.076
41	18	1.321	1.404	-0.083
41	7	1.322	1.408	-0.086
41	2	1.317	1.394	-0.077
41	12	1.321	1.411	-0.089
	Max	1.333	1.428	-0.072
	Average	1.322	1.408	-0.086
	Min	1.317	1.394	-0.095
	Std Dev	0.004	0.008	0.007



	INPUTB THOLD LEVEL			
Test Site				
Tester				
Test Number				
Max Limit	2			
Min Limit	0.8			
kRad	30	31	40	41
LL	0.800	0.800	0.800	0.800
Min	1.408	1.408	1.396	1.394
Average	1.414	1.411	1.402	1.403
Max	1.428	1.415	1.408	1.411
UL	2.000	2.000	2.000	2.000



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